

# The BaBar Detector's Influence on Accelerator Operations and the $f_{D_s}$ Measurement at BaBar

1/28/2009

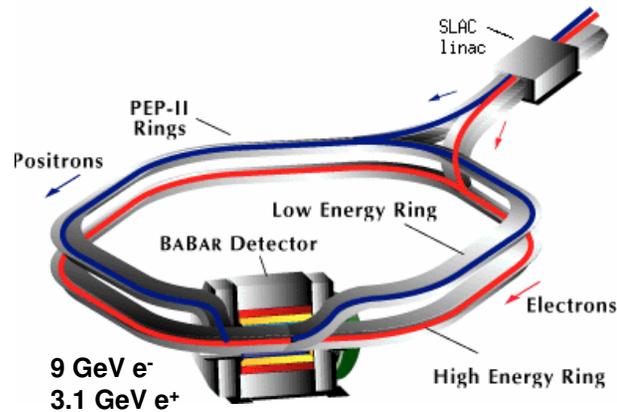
Shane C. Curry  
SLAC / UC Irvine



# Road Map

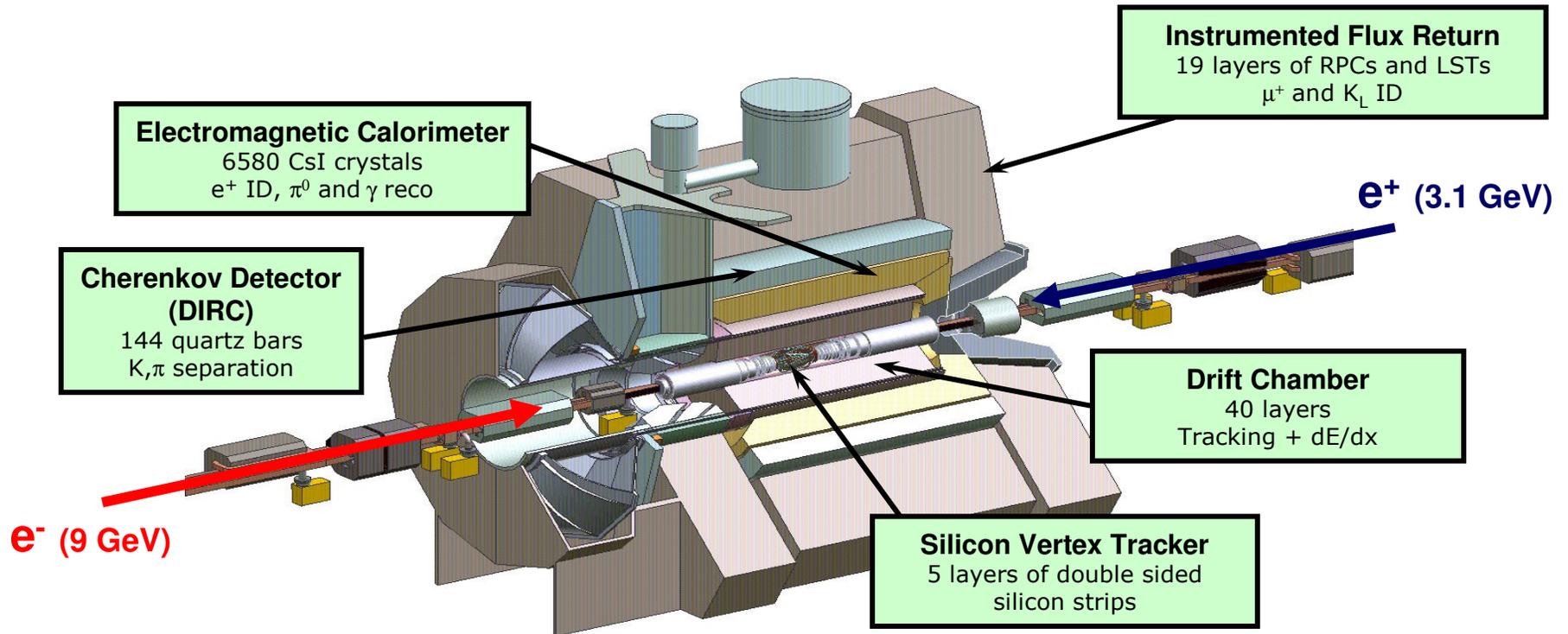
- SLAC and BaBar Overview
- Machine Detector Interface Group
- Detector Protection
  - Dose Rate Monitoring
  - Beam Aborts
  - Trickle Injection
- Accelerator Performance
- Feedback to Operators
- BaBar Analysis
  - Measurement of  $f_{D_s}$

# SLAC (PEP-II) / BaBar



Electron Positron Collider  
Asymmetric B Factory

Peak Lumi -  $12.069 \times 10^{33} \text{ cm}^{-2} \text{ sec}^{-1}$   
2069mA HER 3213mA LER



# Machine Detector Interface Group

## Evaluate Effects of Machine Backgrounds

- Radiation Monitoring
  - Beam Abort Policies
    - Procedure/Threshold Evaluation
  - Detector Subsystem Operational Issues
- Long Term projections
  - Detector Lifetime
- Simulations
  - GEANT - IR description
- Parameterization
  - Forward Shield Wall

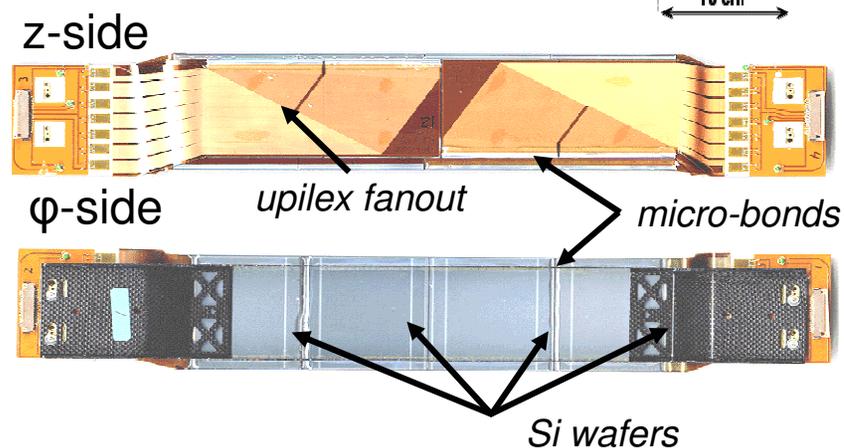
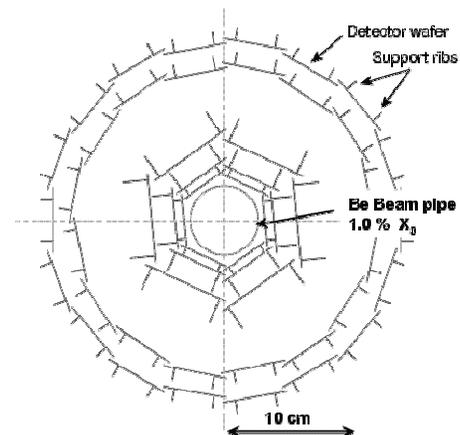
## Accelerator Performance

- Machine Tuning
  - Trickle Injection
  - Detector Occupancies
  - Backgrounds
- Beam Size Measurements
  - BaBar Data ( $e^+e^-$ ;  $\mu^+\mu^-$ )
- Beam-Beam Simulations

### Goal:

Provide operational feedback to operators to improve machine performance and reduce possible downtime.

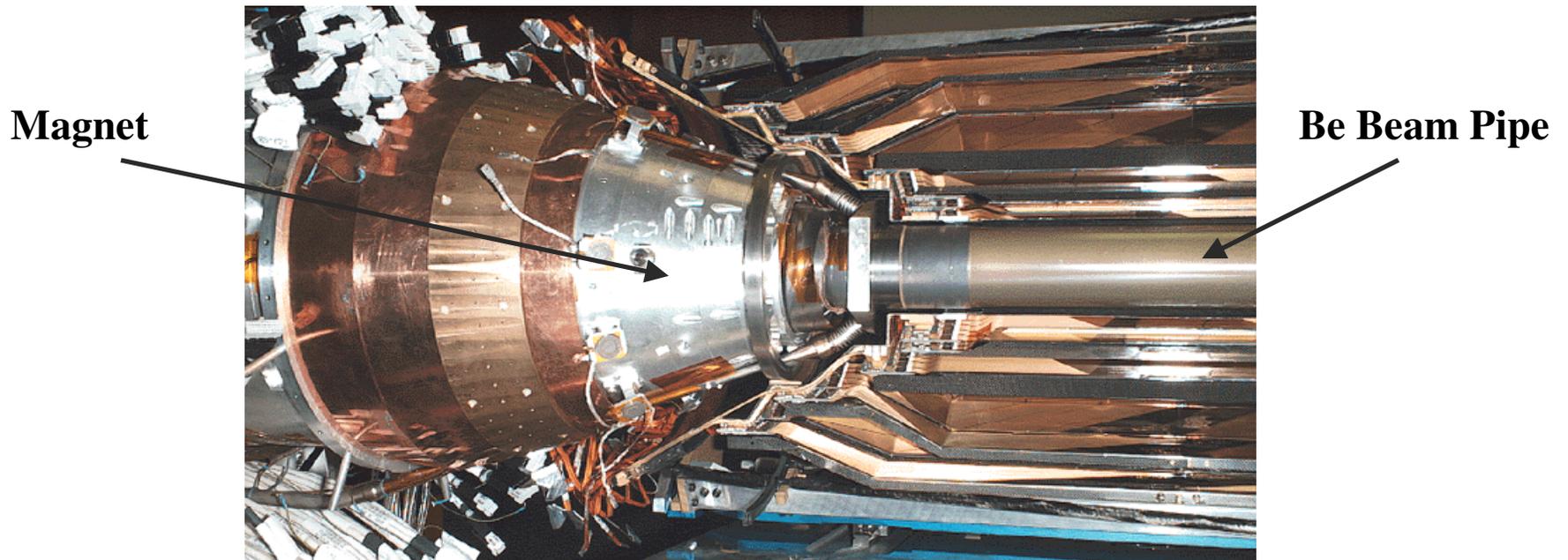
# Silicon Vertex Tracker



- 5 Layers of Double-Sided, AC-Coupled Silicon, 0.94 m<sup>2</sup> of Si
- $\Phi$  and z Strips
- Custom Rad-Hard Readout IC (the AToM Chip).
- Low-Mass Design (Kevlar/Carbon Fiber Mechanical Support)
- Inner 3 Layers: Precision Vertexing
- Outer 2 Layers: Pattern Recognition, Low  $P_{\pm}$  Tracking.

# SVT Protection

- The Silicon Vertex Tracker (SVT), (centimeters from the beam pipe), is highly susceptible to radiation damage
- Receives  $\approx 1$  MRad/yr (electromagnetic)
- Monitored/Protected by the SVT Radiation Monitoring System (SVTRAD)



## SVT Sensors

- Leakage Current Increase
- Shift of Depletion Voltage
- Loss of Charge Collection Efficiency
- P-Stop Shorts

## SVT Readout Electronics

- Noise Increase
- Gain Decrease
- Pedestal Increase

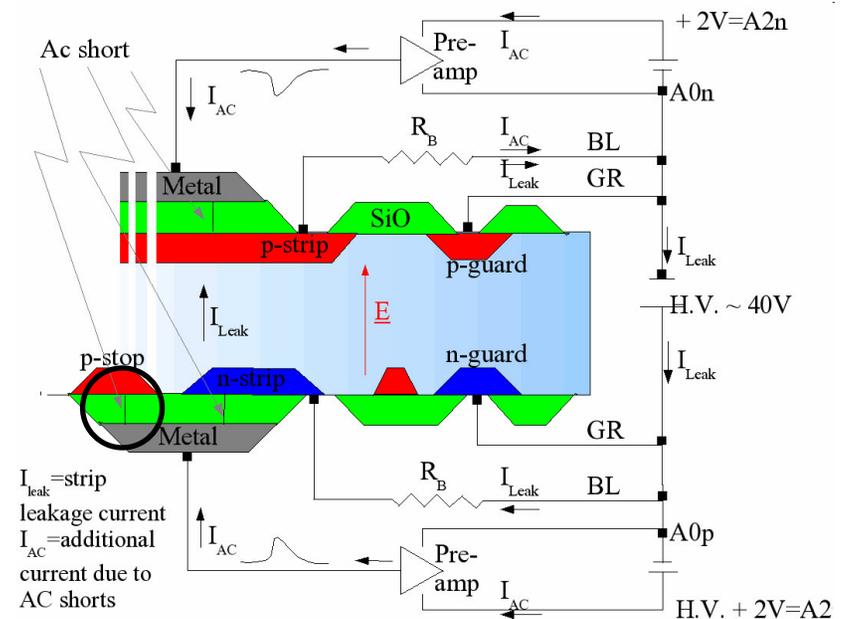
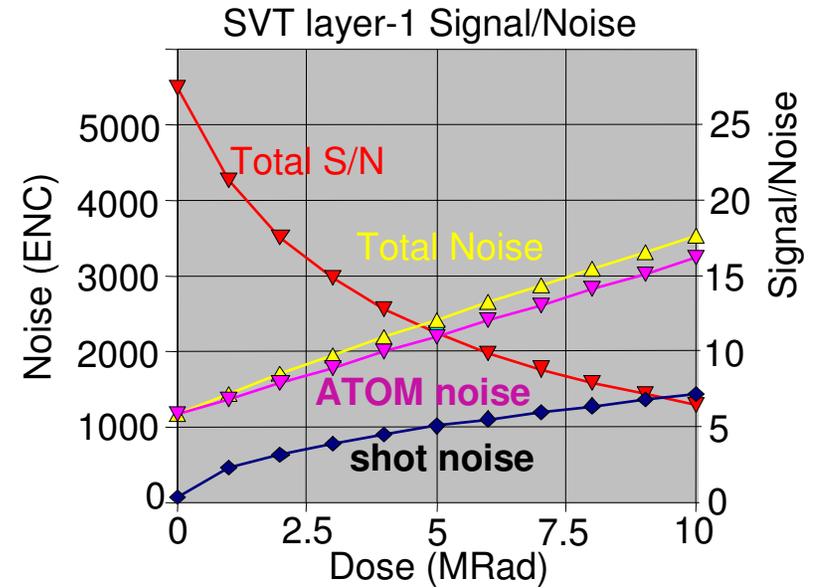
# SVT Protection

## Monitor/Limit Dose Rates:

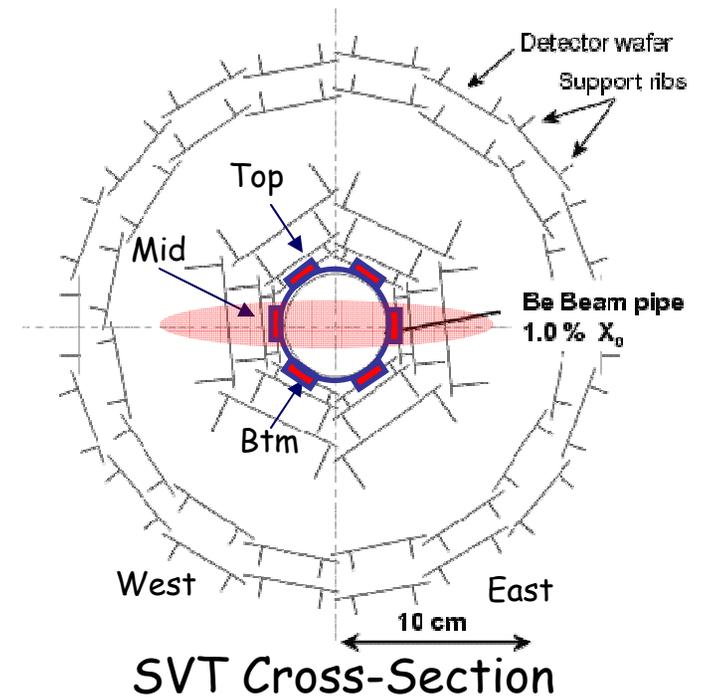
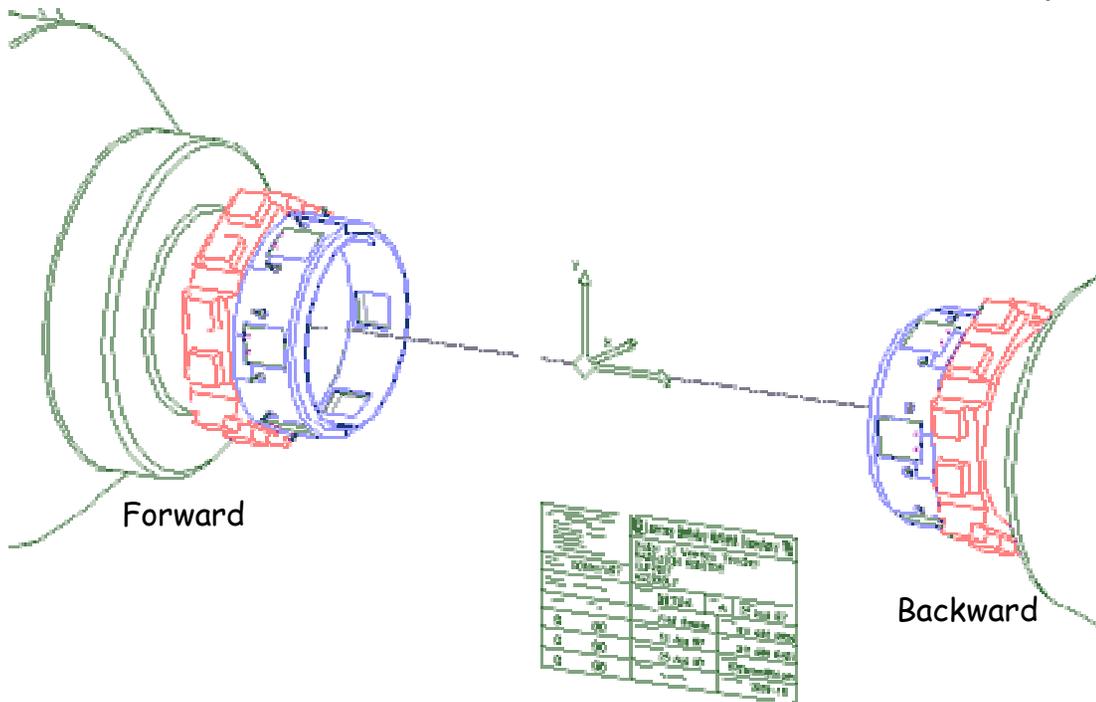
- Limit S/N for Optimum Performance
  - $S/N < 10$
- 5 MRad Radiation Budget
  - Chronic Threshold  $\sim 100$  mRad/s
    - 10 Minute Timer
    - Dump Beams
- Damage to SVT - (p-stop shorts)
  - Acute Threshold  $\sim 1000$  mRad/s
  - Dump Beams

## Protection System Limits How Hard the Machine is Pushed

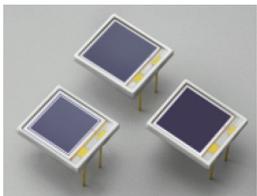
- Startup
- Scrubbing
- Steering



# SVTRAD System



## 12 Silicon PIN Diodes



- 1cm x 1cm x 300 $\mu$ m
- 50V Reverse-Biased
- 6 Diodes Forward Side
- 6 Diodes Backward Side

## 2 pCVD Diamonds



- 1cm x 1cm x 500 $\mu$ m
- 500V Bias
- 1 DM Backward East
- 1 DM Backward West

# Background Categories

## 1. Beam Gas Interactions - Chronic Thresholds

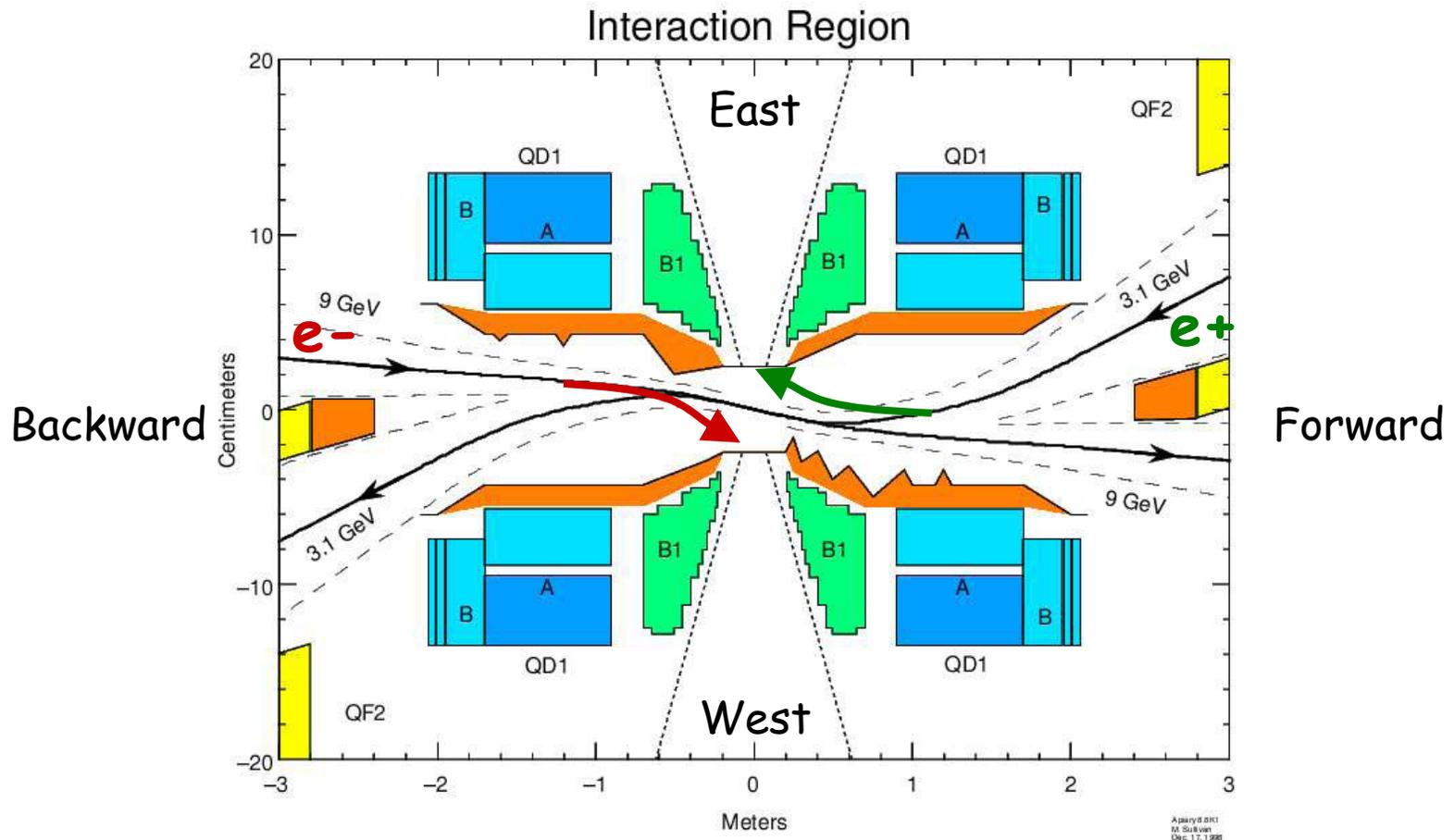
- Bremsstrahlung ( $e + H \rightarrow e + \gamma + H$ )
- Coulomb scattering ( $e + H \rightarrow e + H$ )

## 2. Beam "Instabilities" - Acute Thresholds

- Something causes "wild" background and SVTRAD system dumps both beams in ~1-100ms
- Some Known Causes: Beam Instabilities, Pressure Bursts, "dust" events

## 3. Trickle Injection

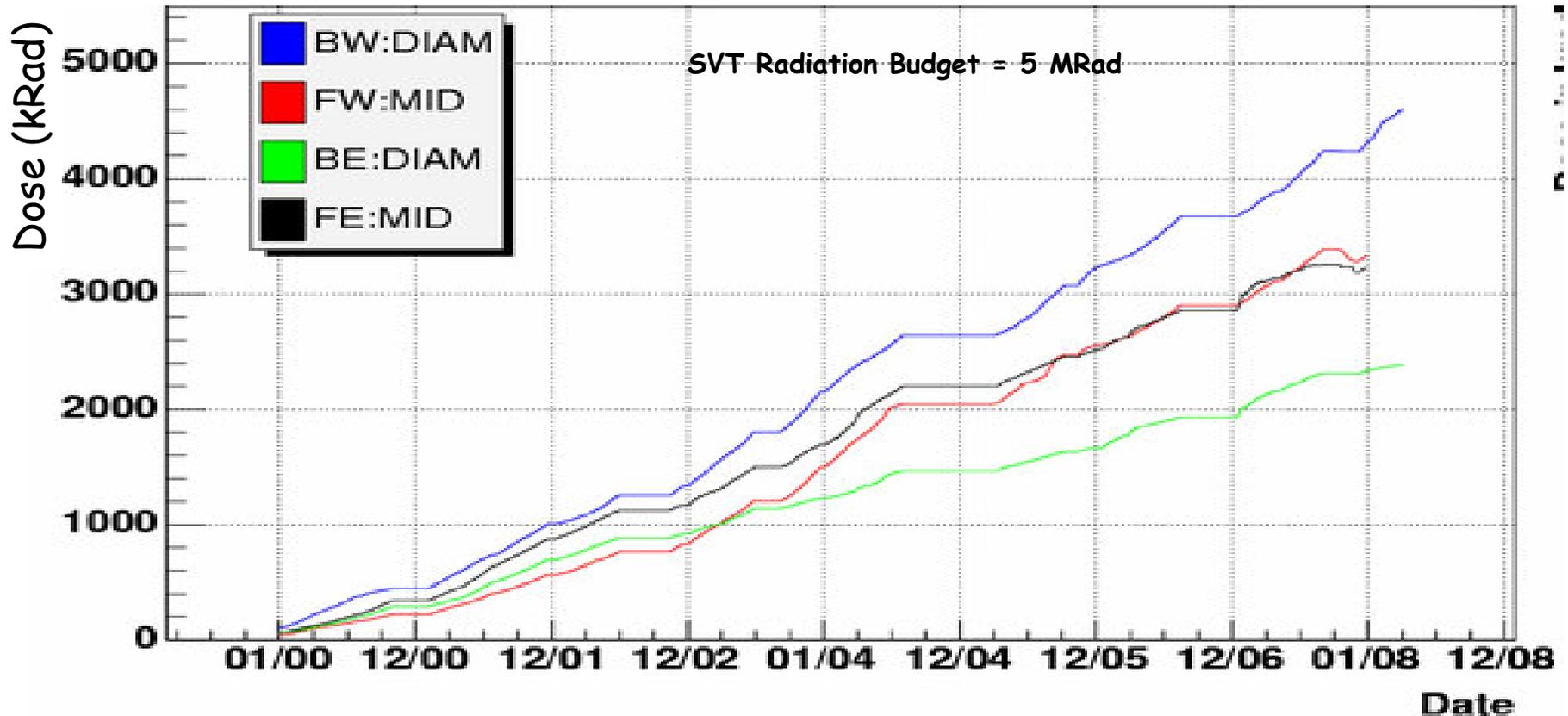
# Beam Gas Backgrounds



- Off Energy/Angle Electrons Hit West Midplane Diodes
  - Largest Source of Radiation of Chronic Radiation
- Off Energy/Angle Positrons Hit East Midplane Diodes

# Monitoring - Total Integrated Dose

## Mid-Plane Diodes/Diamonds

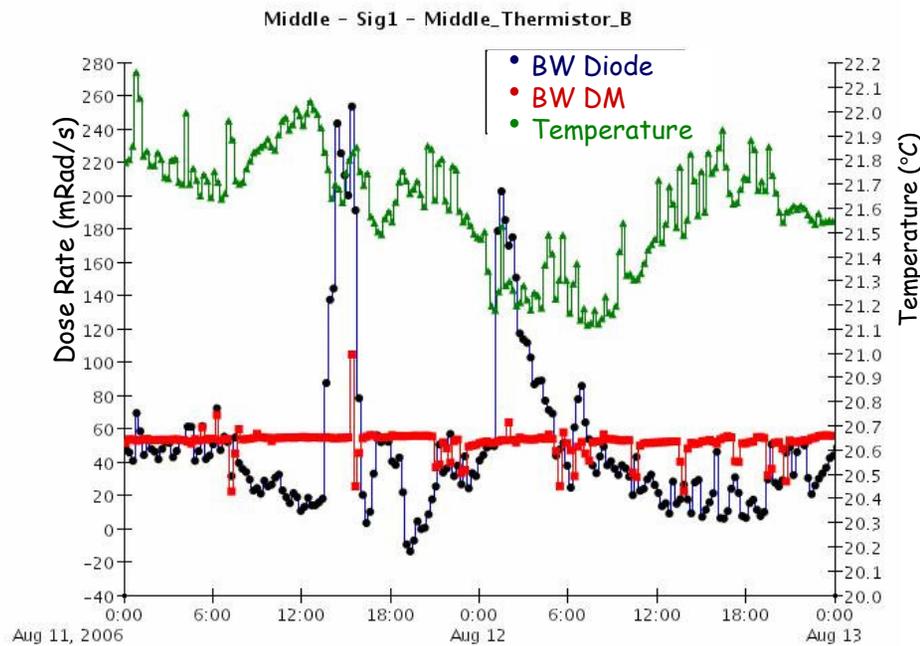


Limiting Dose Rates to Under 100 mRad/s  
Allowed the Total Integrated Dose to Remain  
Below Budget of 5 MRad Over the Lifetime of BaBar  
and Ensured Optimum Detector Performance

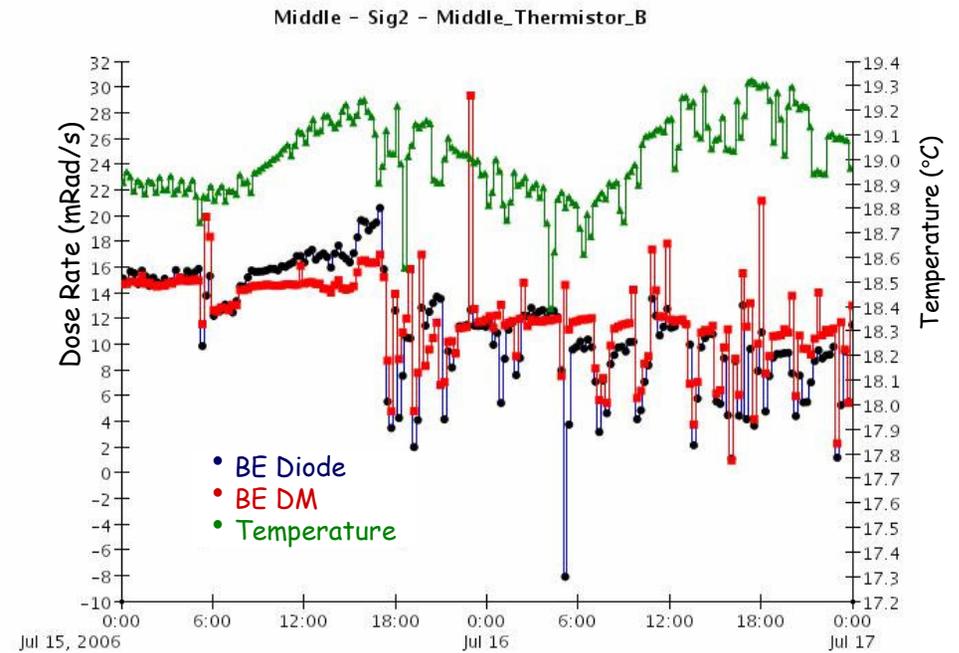
# Monitoring - Diodes vs Diamonds

- Machine Operator's Frustrations
  - Inconsistent Diode Performance
  - Increasingly Difficult to Operate Diodes Due to Radiation Damage
  - MID Plane Diodes Replaced by Diamonds for Monitoring

## BW-MID Diode vs BW-MID DM



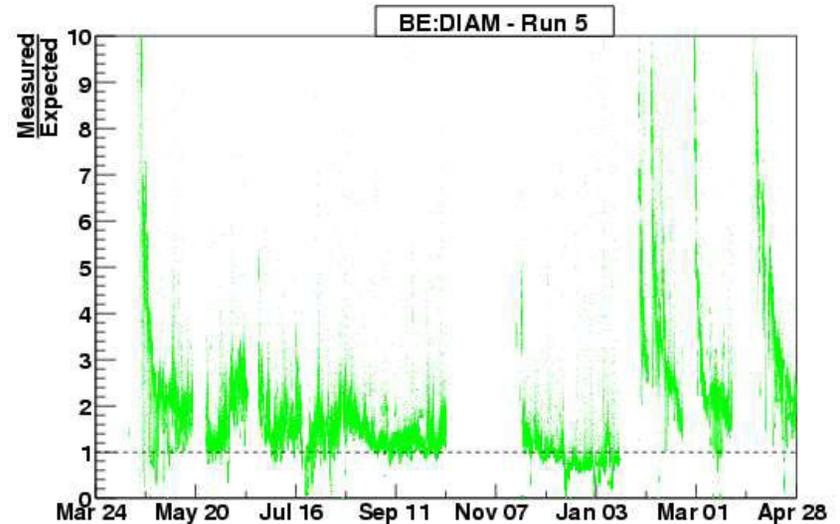
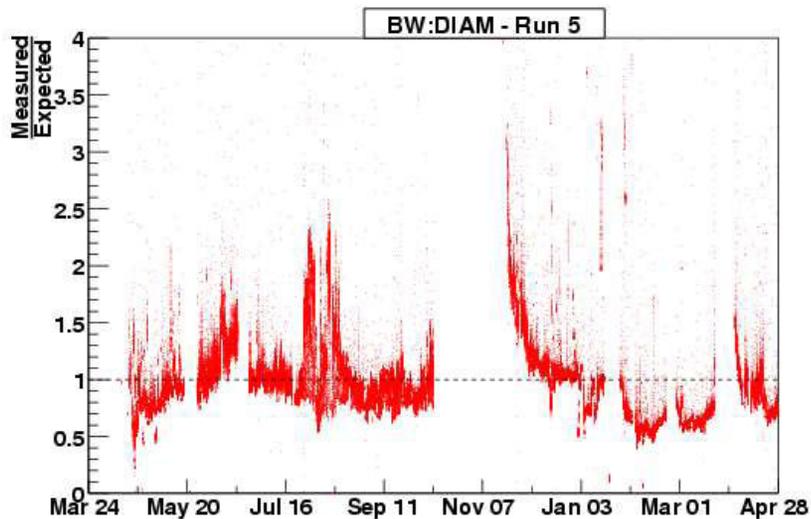
## BE-MID Diode vs BE-MID DM



# Measured vs Expected Dose Rates

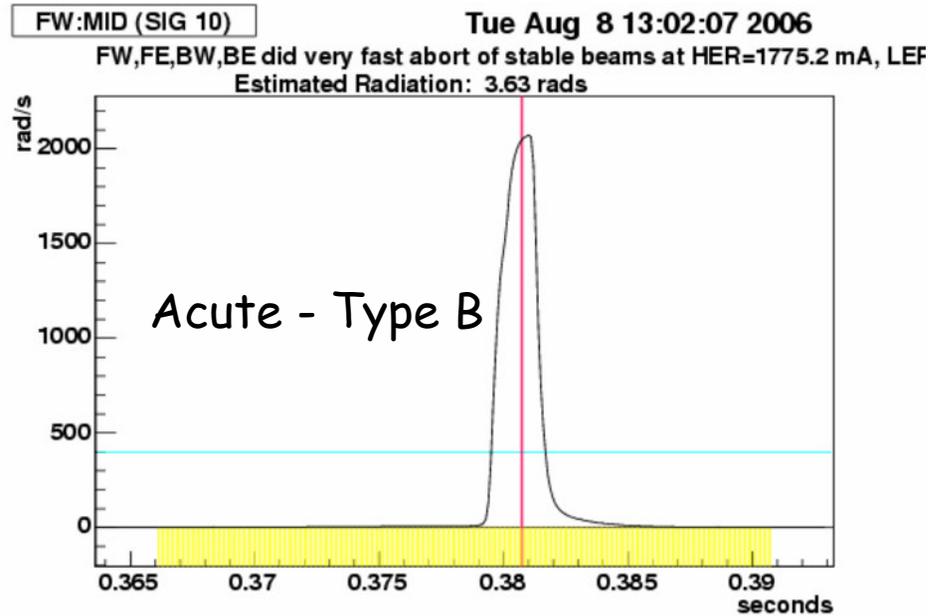
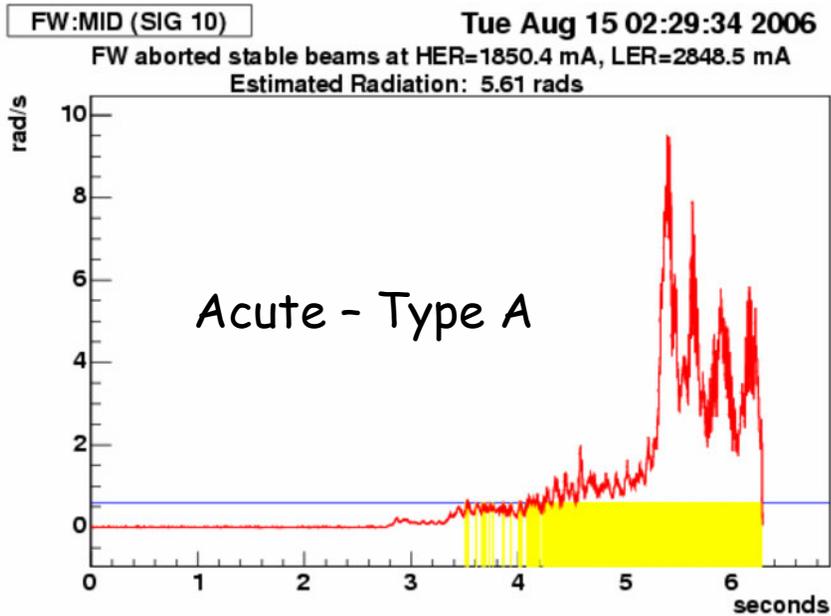
## Expected Dose Rate

- Is the Current Level That Bad?
- Function of:
  - HER Current
  - LER Current
  - Luminosity
- Measured During Stable Running
  - Single Beams
  - Colliding Beams



Can see periods where the vacuum was broken

# Protection - Beam Aborts



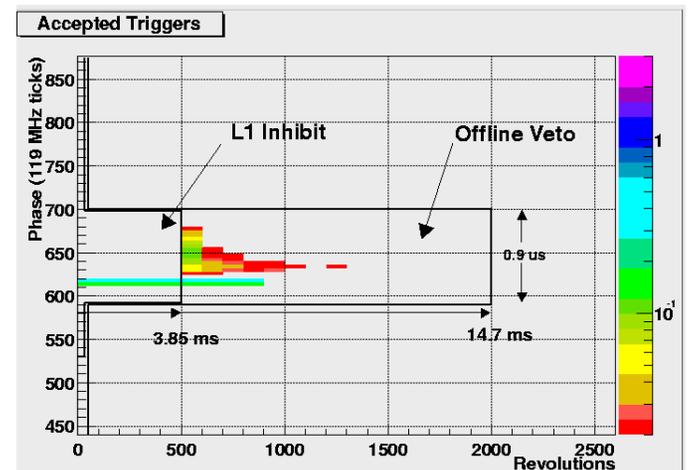
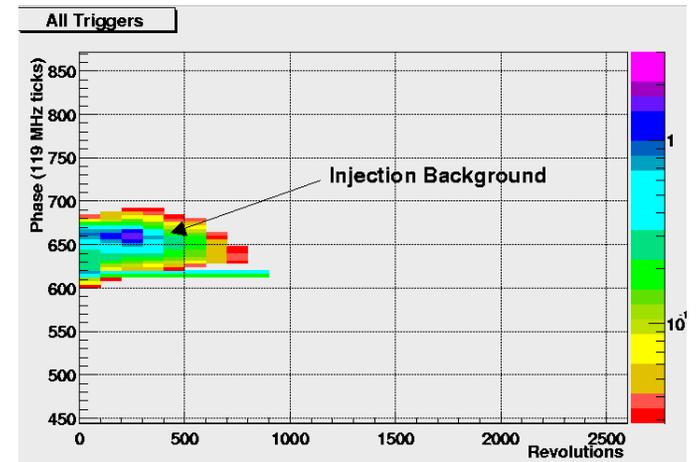
## Radiation Damage Protection - Beam Aborts

- "Acute" - Fast Radiation Damage
  - A - Dose Rate  $> 1000$  mRad/s and Integrates to 5 Rad
  - B - Dose Rate  $> 400$  Rad/s
- "Chronic" - Integrated Radiation
  - Dose Rate  $> 100$  mRad/s for 10 minutes - "10 Minute Timer"
  - Control "Unnecessary" Doses

# Trickle Injection

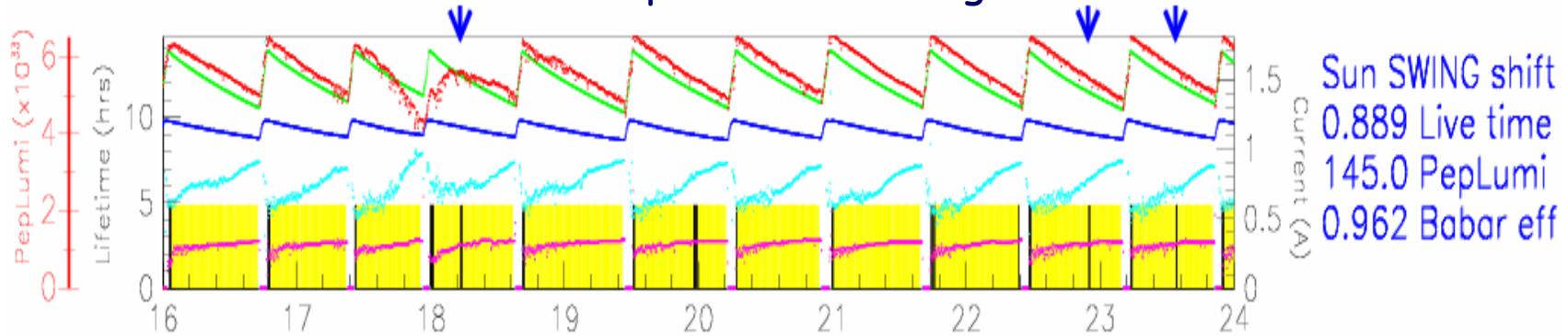
Injection is necessary to refill beam "buckets" which have lost charge. A particular bucket is targeted for each injection shot.

- Important factor in increasing integrated luminosity.
- Keep LER/HER at constant current by continuously injecting positrons/electrons at 1-30Hz.
- The injected bunch causes backgrounds in BaBar.
  - "Upsets" detector electronics
  - Increases detector deadtime
    - An L1 trigger inhibit window around injection is used to control dead-time.



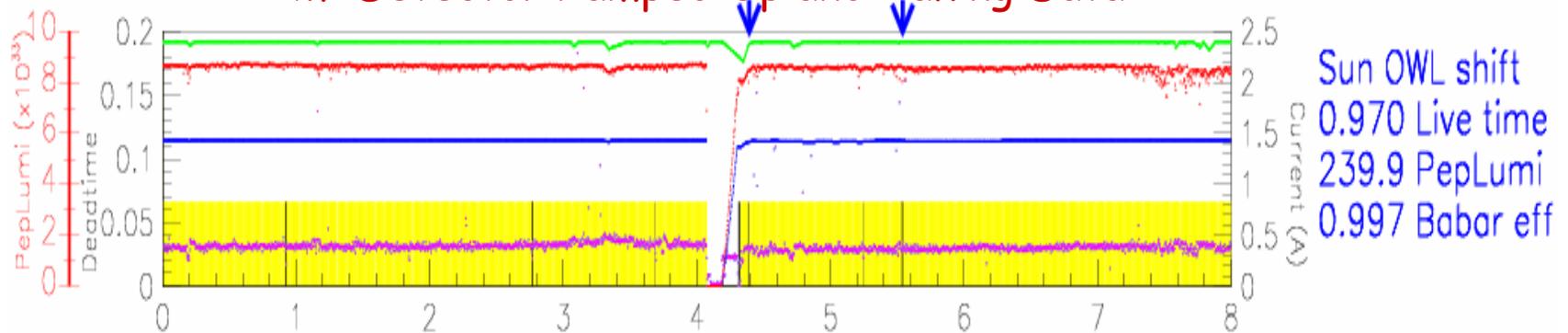
# Trickle Injection

Fill and Coast  
Detector Ramped Down During Fills



- HER Current
- LER Current
- Luminosity

Continuous Trickle of HER and LER  
w/ Detector Ramped Up and Taking Data

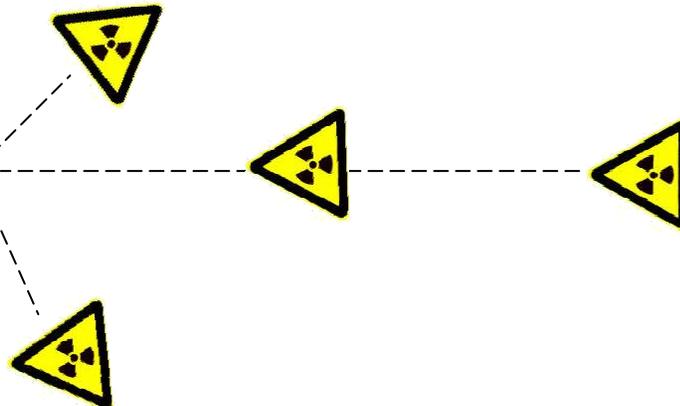
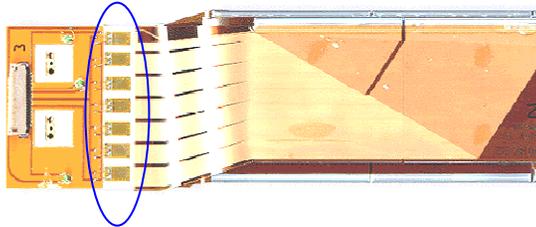


# SVTRAD Trickle Injection Monitoring

## SVTRAD Flexibility:

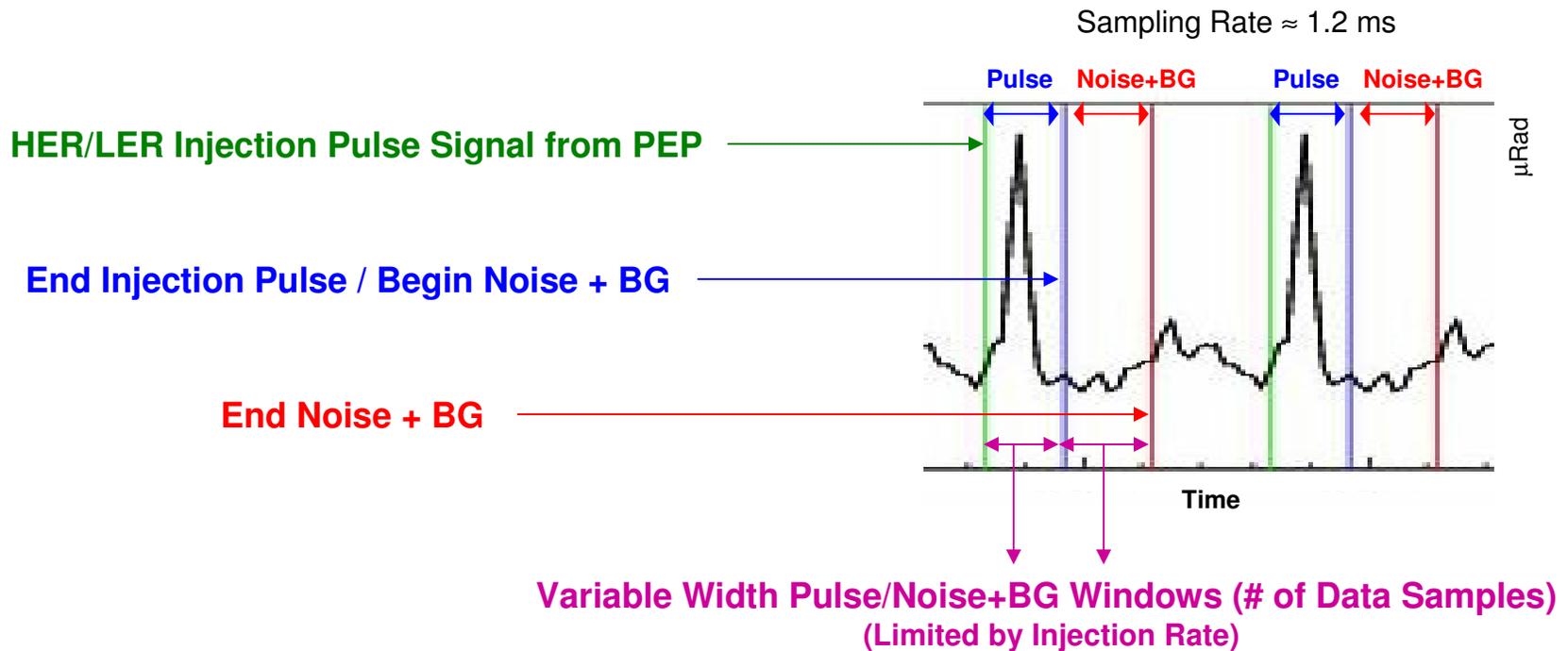
- Injection Monitoring
  - Provide Injection Quality Feedback to Machine Operators
  - Identify Probable SVT "Configuration Loss" Periods
    - Reset of Front End Electronics = "Configuration Loss"
    - Data Taking is Stopped While SVT is Reconfigured

Burst of Radiation Causes  
SVT AToM Chips to Reset,  
Results - Corrupted Data

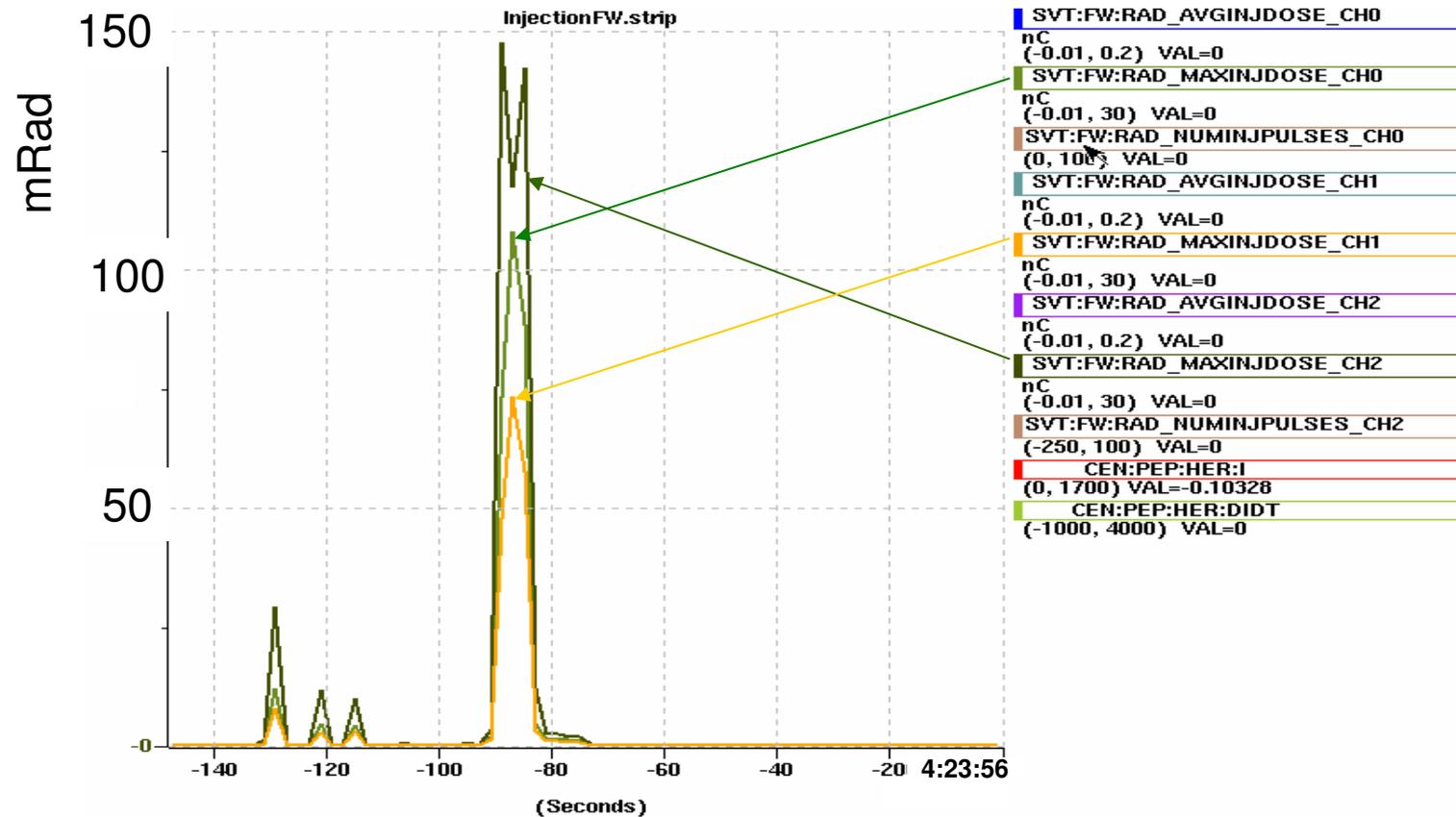


# Injection Monitoring Logic (On Board)

1. Receive: **Injection Pulse Signal from PEP**
2. Integrate: **Pulse**
3. Integrate: **Noise + Stable Beam Background**
4. Dose = **Pulse** - (**Noise + BG**) → No Temperature Dependence
5. Reported as EPICS Variables: **Max Dose : Avg Dose : # Injection Pulses**  
(Report Max Dose Over 2 Seconds and Average Dose Over 2 Seconds)

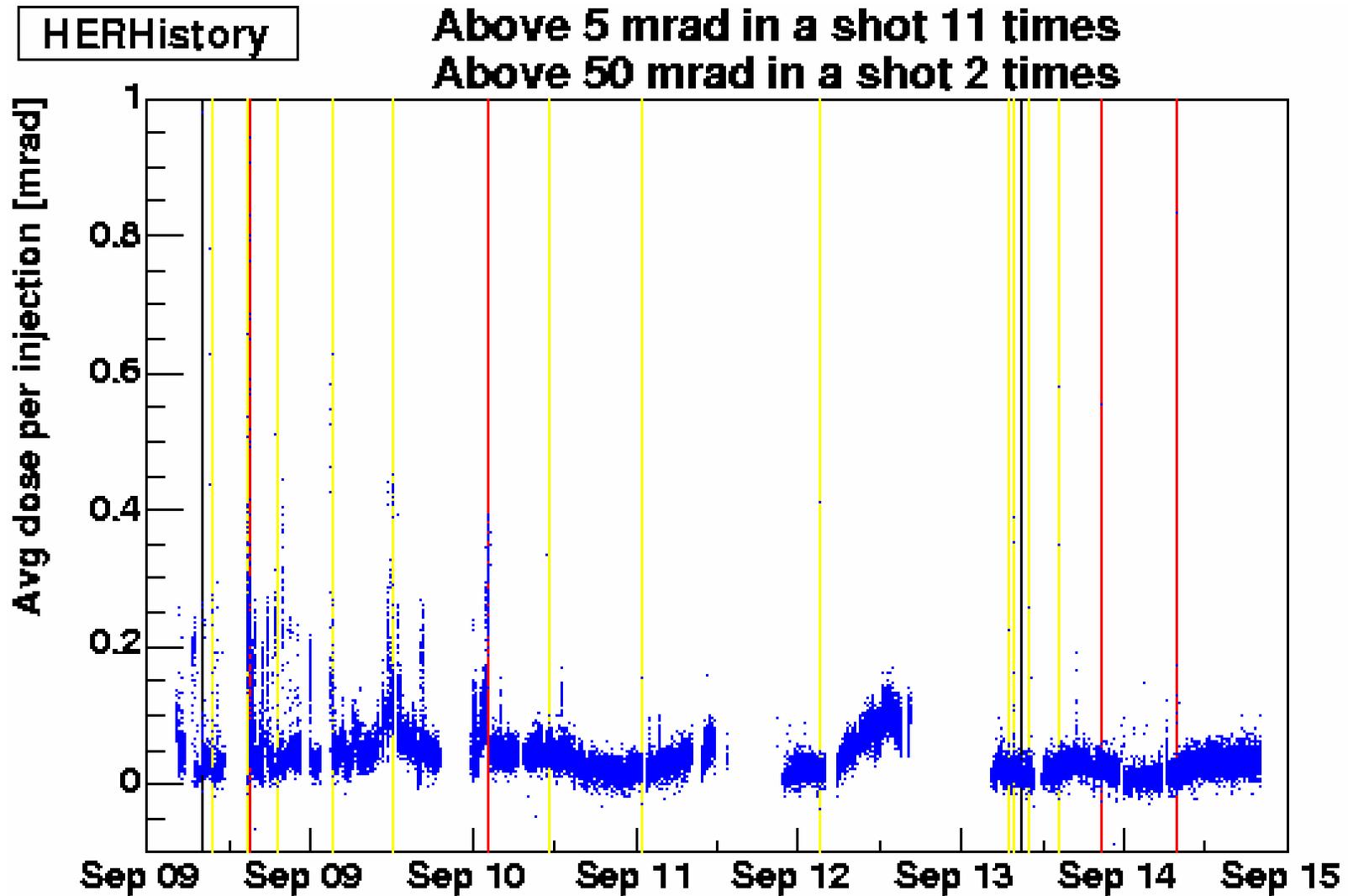


# Run Stopped due to SVT Damages



- Able to Correlate SVT Configuration Losses with Large Spikes in Injection Dose
- Injection Quality Alarms Warn of Possible Losses
- Implemented Automated SVT Reconfiguration
  - Limits Downtime

## HER Injection Monitoring Summary

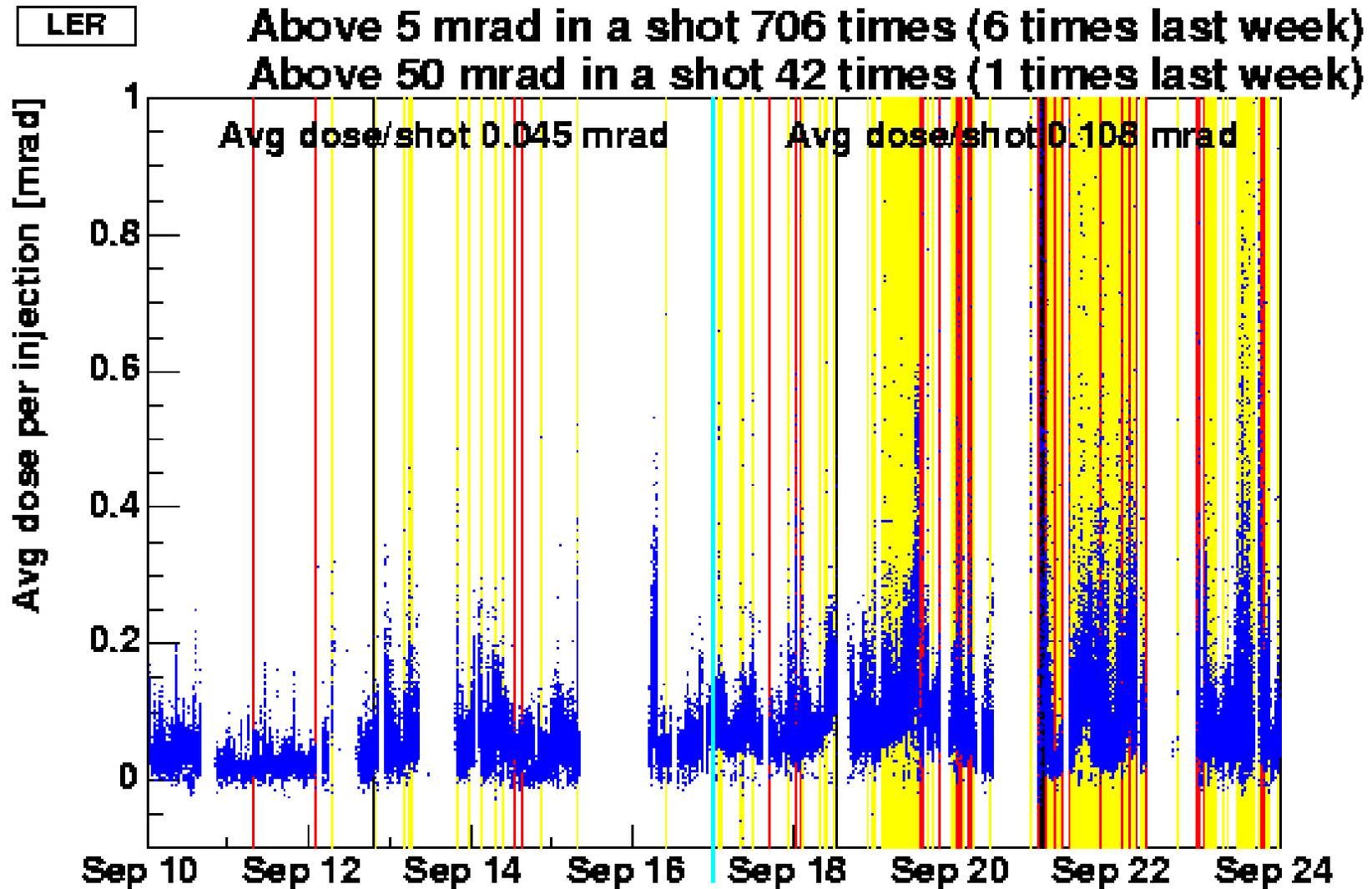


Yellow – Max Inj Dose above 1 mRad

Red – Max Inj Dose above 5 mRad

Black – Max Inj Dose above 50 mRad (SVT Configuration Losses)

## LER Injection Monitoring Summary

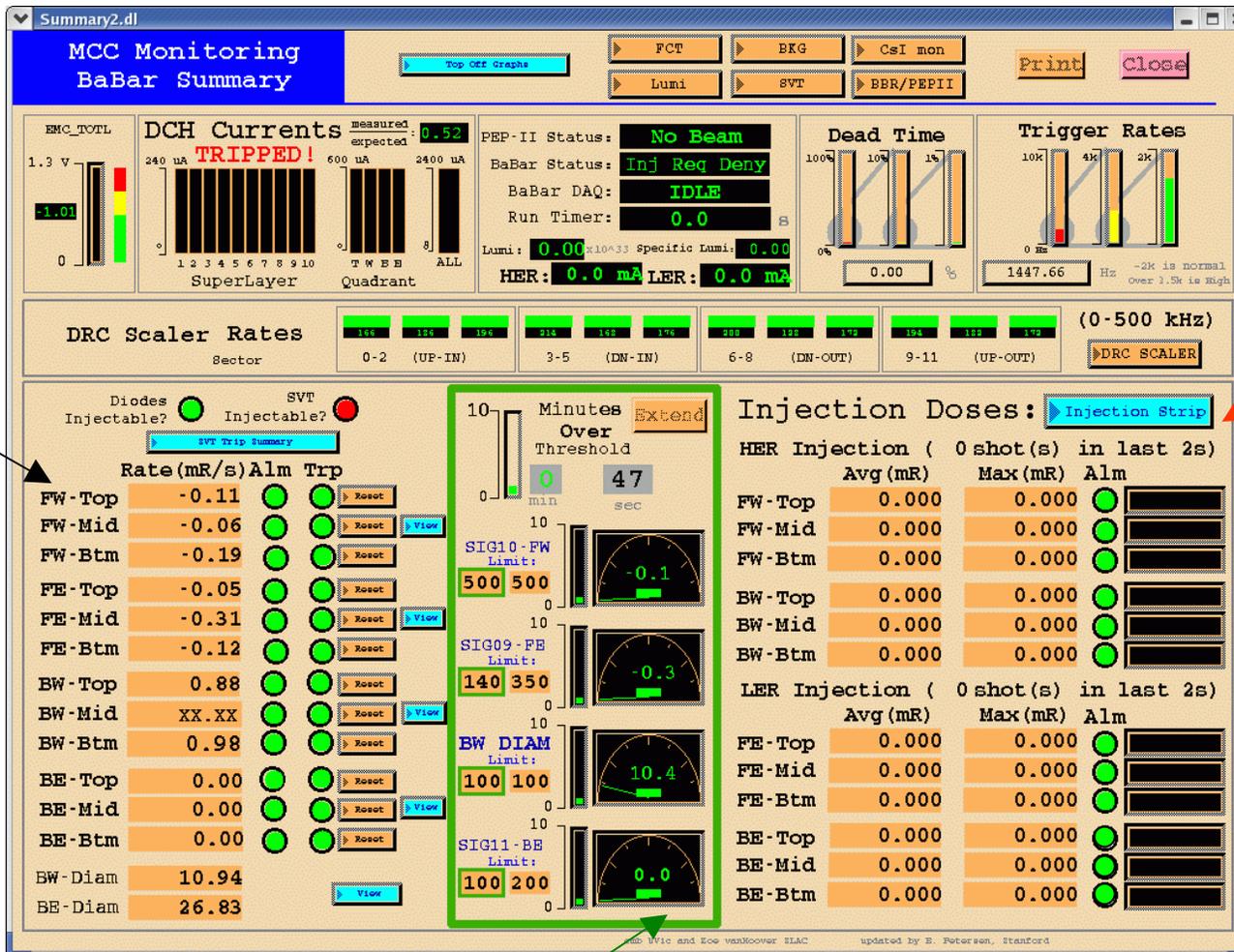


Yellow – Max Inj Dose above 1 mRad

Red – Max Inj Dose above 5 mRad

Black – Max Inj Dose above 50 mRad (SVT Configuration Losses)

# Machine Operators Background Panel



Dose Rates

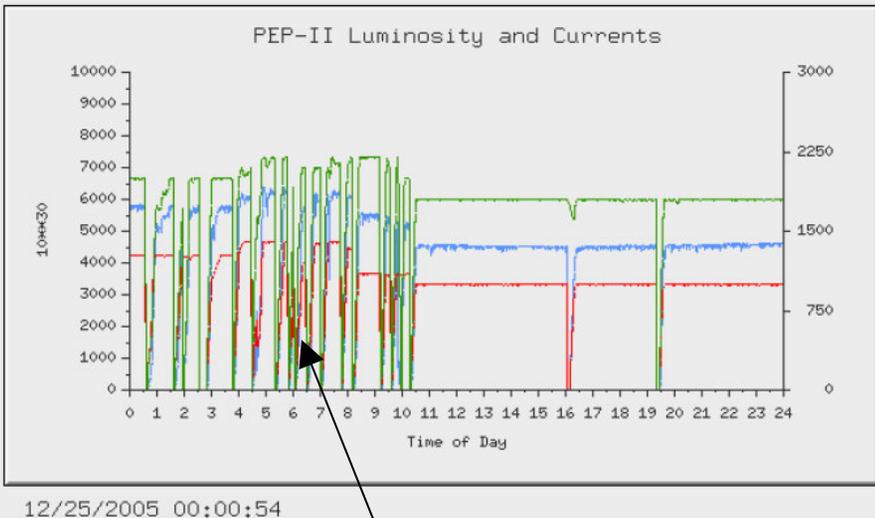
Injection Monitoring

10 minute timer

Provide Background Quality Feedback to Machine Operators for Tuning the Machine to Allow Better Detector Environment and Data Taking Conditions

# Diagnosing Machine Issues

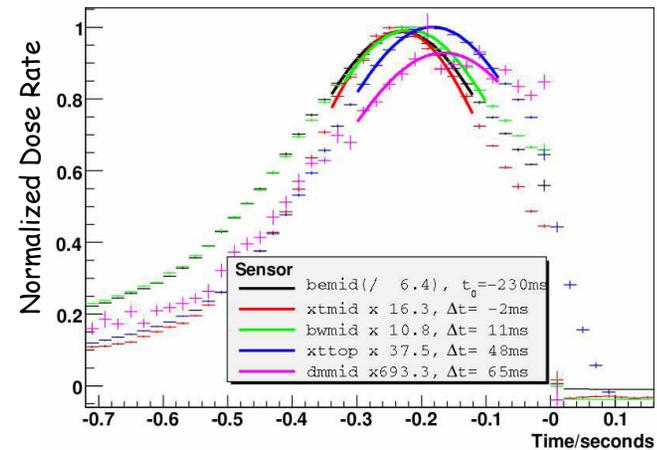
I HER	I LER	Luminosity	Spec Lum	E HER	E LER	E CM
999.97	1800.64	4550	4.35	8986	3120	10590
mA	mA	$10^{30}/\text{Sec}$	$\text{N}^{10^{30}} / \text{mA}^{2}/\text{Sec}$	MeV	MeV	MeV
HER N Buckets / Pattern			LER N Buckets / Pattern			
1722 0:3442:2=1			1722 0:3442:2=1			
Last Owl/Day/Swing/24hr		89.2	111.4	122.7	323.3	Shift: 0.28 /pb
Peak Luminosities		6458	6203	4656	4643	



Excessive Number of Radiation Aborts  
At High HER & LER Currents

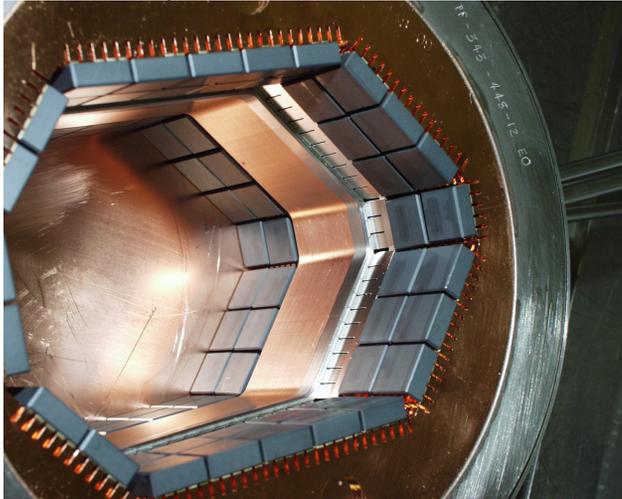
## Diagnose:

- Borescoping
- Increased Abort Threshold
- Vacuum Gauges
- Temperature Gauges
- Timing Difference of Diodes
- ...



# Damage to Bellows and RF Seal

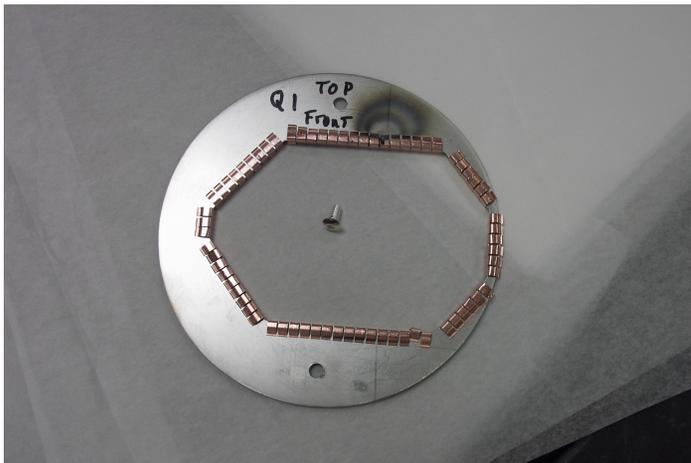
Before Installation



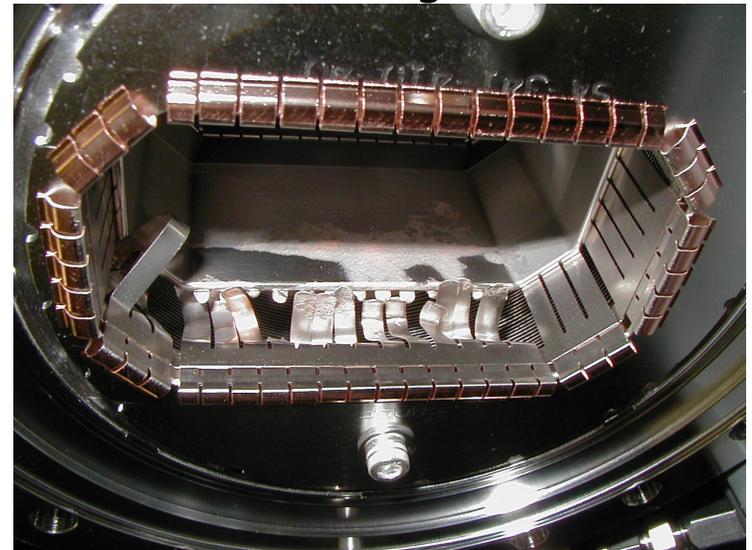
Damage



Damage



Damage



# Results

## Monitoring

- Balance:
  - Detector Performance
  - Integrated Luminosity

## Aborts

- Detector Protection
- Downtime: Refill Machine

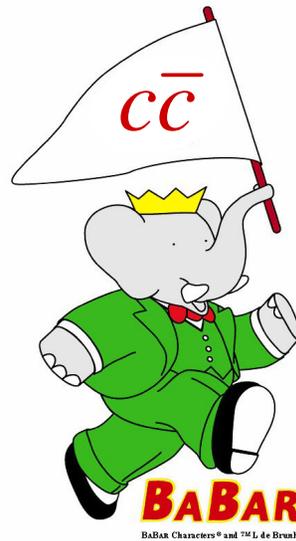
## Trickle

- Downtime Due to Configuration Losses

A lot of time and effort goes into reducing the amount of downtime for the machine and data taking. Detector subsystems can contribute to machine performance. Cooperation between machine operations and detector personnel helped to achieve a large and quality data sample for precision particle physics analysis.

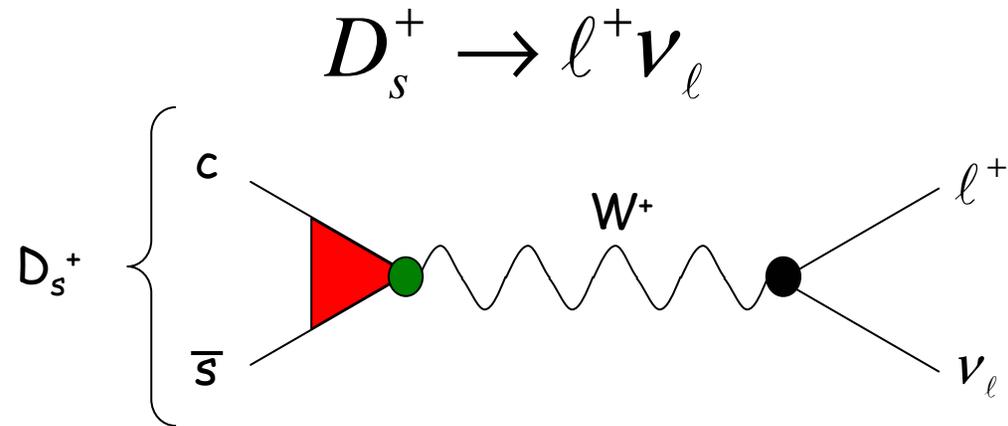
# BaBar Analysis

## Measurement of the $D_s \rightarrow \tau \nu_\tau$ Branching Fraction and Extraction of the Pseudoscalar Decay Constant $f_{D_s}$



(Not Just a B-Factory)

# $D_s$ Pseudoscalar Decay Constant



## Decay Rate for Purely Leptonic $D_s^+$ Decay\*:

$$\Gamma(D_s^+ \rightarrow \ell^+ \nu_\ell) = \frac{G_F^2}{8\pi} m_{D_s}^3 \left( \frac{m_\ell^2}{m_{D_s}^2} \right) \left( 1 - \frac{m_\ell^2}{m_{D_s}^2} \right)^2 (V_{cs})^2 f_{D_s}^2$$

Helicity Suppression
Phase Space

- $m_\tau$  close to  $m_{D_s}$ 
  - Combined Helicity and Phase Space  $\gg e/\mu$
- Ratio of Decay Rates:  $e : \mu : \tau = 2 \times 10^{-5} : 1 : 10$

\* The use of charge conjugation is implied throughout

# Motivation

- Experimental measurements of  $f_{D_s}$  can help to calibrate and validate lattice QCD
  - Study leptonic decays of heavy mesons
  - Applicable to the CKM suppressed B-meson sector
    - Can use  $f_{D_s}$  to calibrate QCD that predicts  $f_B, f_{B_s}$
- Relative decay rates to different lepton flavors well predicted
  - Deviations imply 'New Physics'
    - 2-Higgs Doublet [1]
    - Leptoquarks [2]

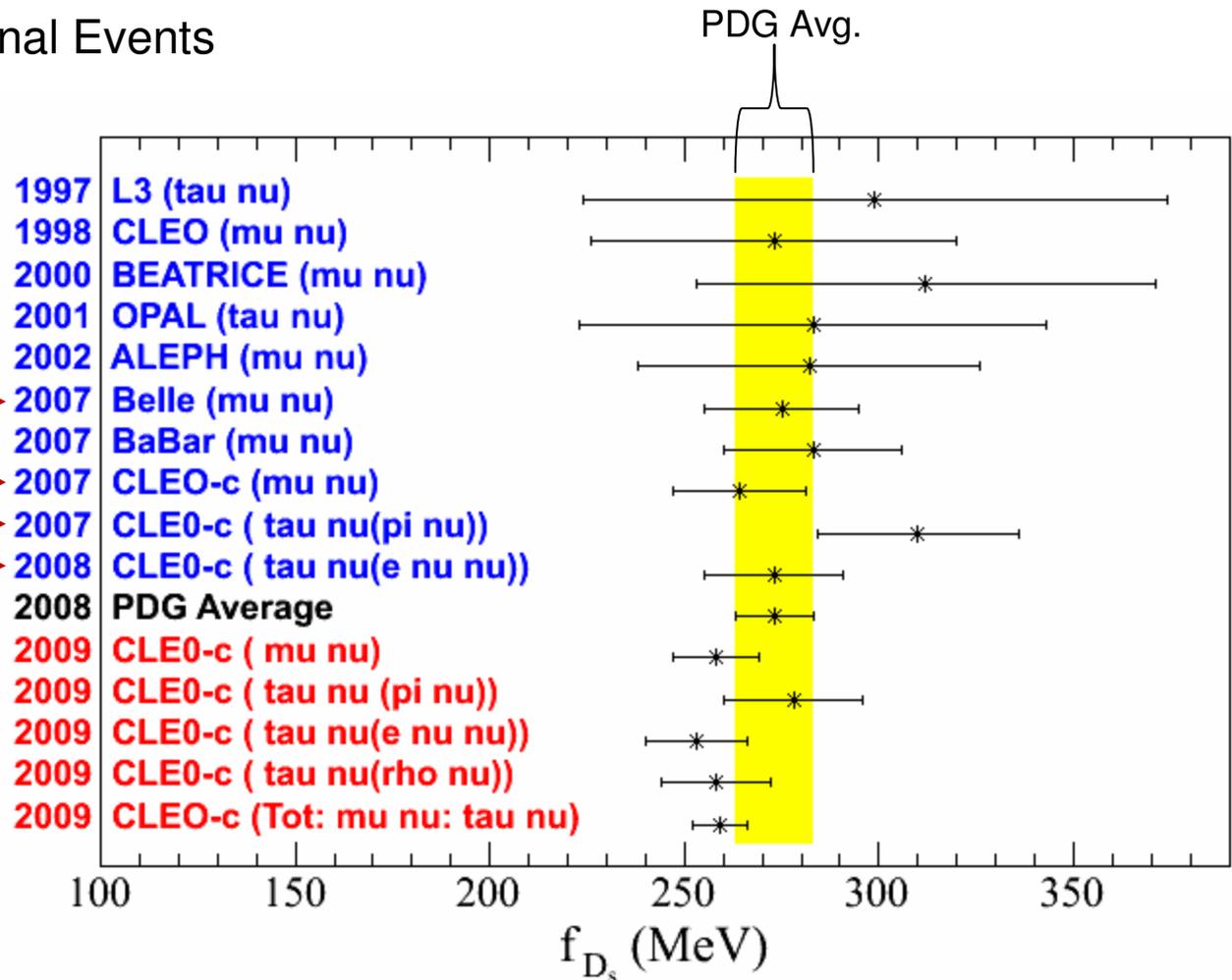
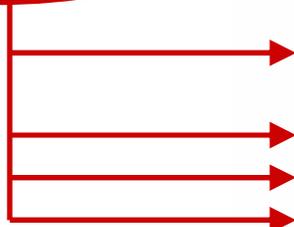
(1) A.G. Akeroyd and C.H. Chen, Phys. Rev. D75, 075004 (2007).

(2) B.A. Dobrescu and A.S. Kronfeld, [arXiv:0803.0512v2] (2008).

# $f_{D_s}$ - Experimental Results

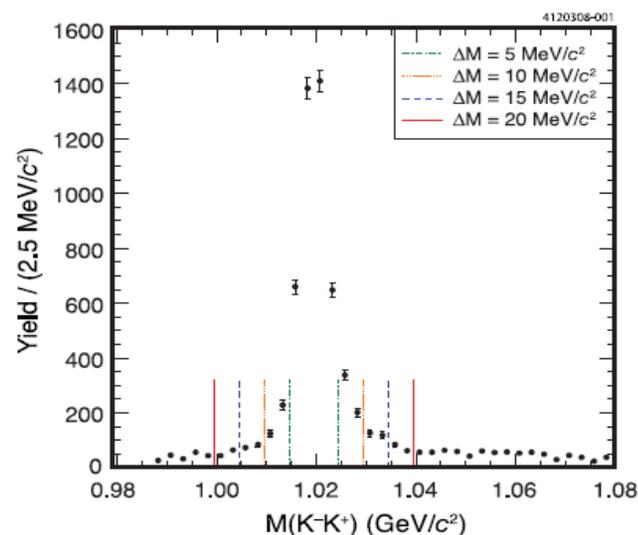
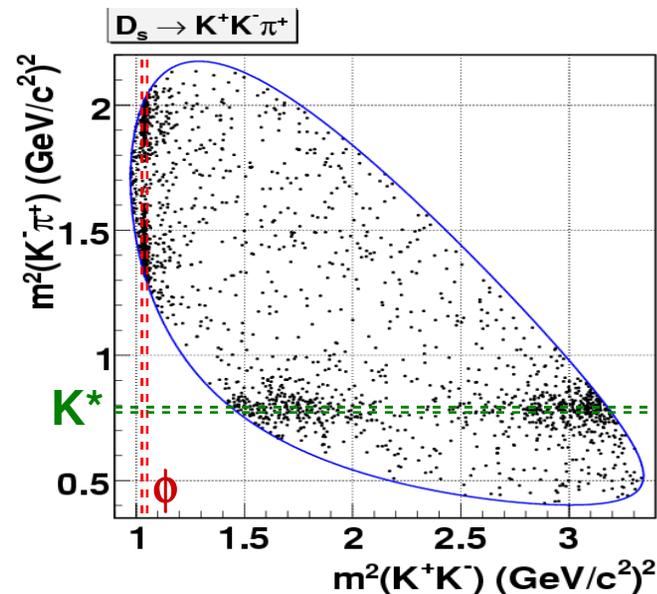
- Only Absolute Measurements are Used for the PDG Average:
  - Relative Measurements Rely on  $B(D_s \rightarrow \phi\pi)$ 
    - Measured Ratio:  $B(D_s \rightarrow l\nu)/B(D_s \rightarrow \phi\pi)$
- BABAR Measurement of  $f_{D_s} : (D_s \rightarrow \mu\nu)$ 
  - $230.2 \text{ fb}^{-1}$
  - 389 Signal Events

Only Measurements Included in PDG Average



# Issues with using $D_s \rightarrow \phi\pi$ for Normalization

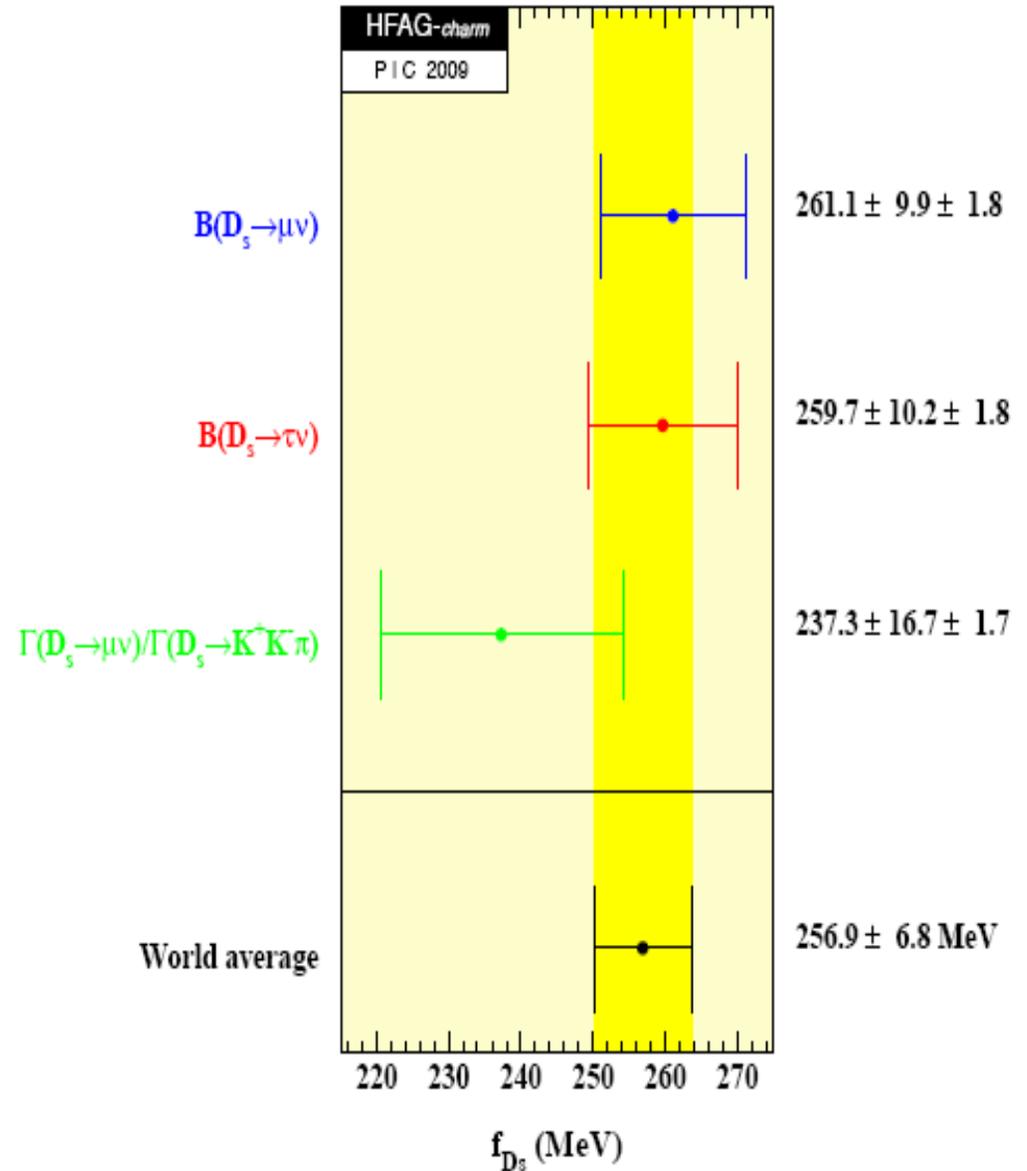
- $D_s \rightarrow \phi\pi$  is used as a normalization mode by many experiments:
  - Not well known
  - Error on  $B(D_s \rightarrow \phi\pi: \phi \rightarrow K^+K^-) \approx 15\%$
  - $f_0(980) \rightarrow K^+K^-$  also contributes
  - Large source of error
- Resonances in the Dalitz plot:
  - Contributions to yields depends on selection criteria [1]
    - $(K^+K^-)_\phi$  Mass Window
    - Resolution
    - Angular Distribution



$(K^+K^-)_\phi$ Mass Window	$B(D_s \rightarrow KK\pi)$ (%)
$\Delta M = 5 \text{ MeV}$	$1.69 \pm 0.08 \pm 0.06$
$\Delta M = 10 \text{ MeV}$	$1.99 \pm 0.10 \pm 0.05$
$\Delta M = 15 \text{ MeV}$	$2.14 \pm 0.10 \pm 0.05$
$\Delta M = 20 \text{ MeV}$	$2.24 \pm 0.11 \pm 0.06$

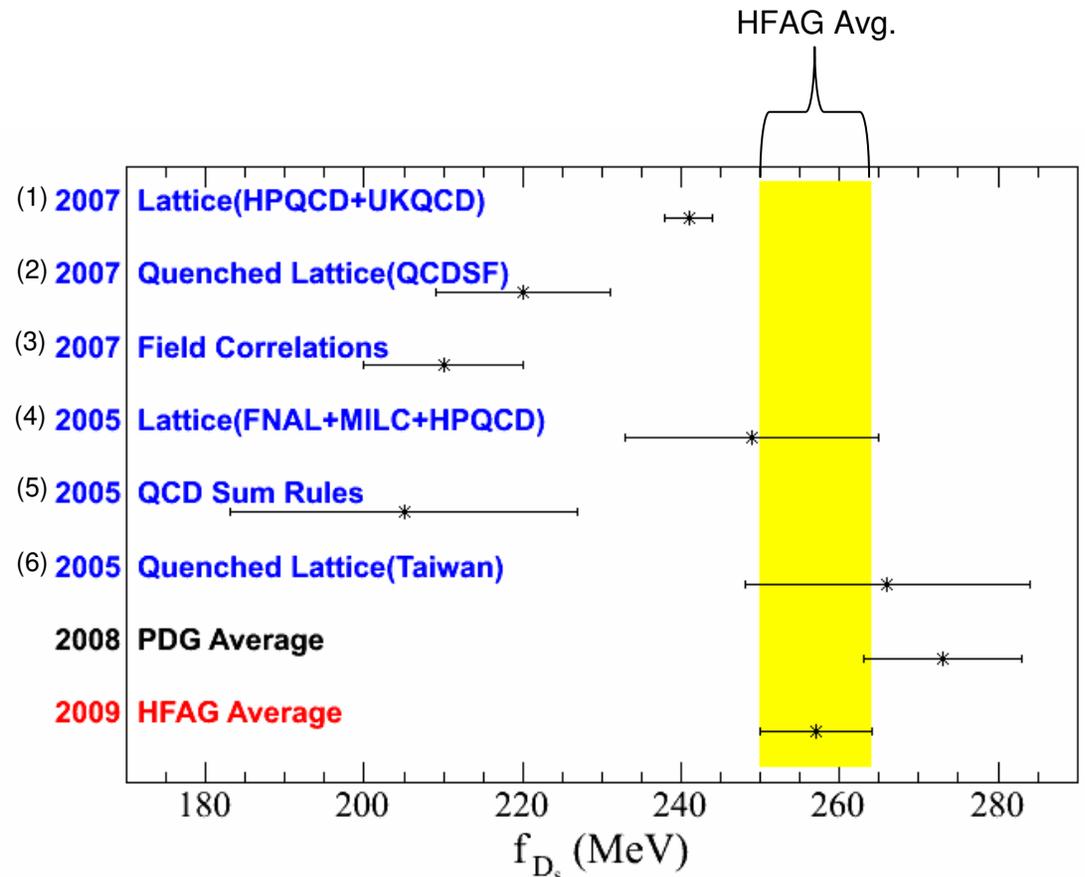
# HFAG Average

- $D_s \rightarrow \mu\nu$ :
  - 2-CLEO-c (2007,2009)
  - Belle (2008)
- $D_s \rightarrow \tau\nu$ :
  - 4-CLEO-c (2007-2009)
  - ALEPH (2002)
  - OPAL (2001)
  - L3 (1997)
- $D_s \rightarrow \mu\nu / D_s \rightarrow KK\pi$ :
  - $|M_{K^+\bar{K}^-} - M_\phi| < 5.5 \text{ MeV}$
  - BaBar (2007)
  - ALEPH (2002)
  - BEATRICE (2000)
  - CLEO (1998)



# $f_{D_s}$ - Theoretical Predictions

- Unquenched Lattice Calc. [1]
  - Includes u,d,s sea
  - $f_{D_s} = 241 \pm 3$  MeV
- Small Error on Theory
  - Motivates Improve Exp.
- PDG Experimental Average
  - $273 \pm 10$  MeV
- HFAG Average
  - $256.9 \pm 6.8$  MeV



- (1) E. Follana *et al.*, (HPQCD and UKQCD Collabs.), Phys. Rev. Lett. 100, 062002(2008)
- (2) A. Ali Khan *et al.*, (QCDSF Collaboation), Phys. Lett. B **652** 150 (2007).
- (3) A.M. Badalian *et al.*, Phys. Rev. D **75**, 116001 (2007).
- (4) C. Aubin *et al.*, (MILC Collaboration), Phys. Rev. Lett. **95**, 122002 (2005).
- (5) J. Bordes, J. Penarrocha, and K. Schilcher, JHEP **0511**, 014 (2005).
- (6) T.W. Chiu *et al.*, Phys. Lett. B **624**, 31 (2005).

# What Will Be Measured?

Measure  $B(D_s^+ \rightarrow \tau^+ \nu_\tau)$  via  $\tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$

Use  $K_S K$  instead of  $\phi\pi$  for Normalization

$D_s^+ \rightarrow K_S K^+$   $(1.49 \pm 0.09)\%$  (corrected for  $K_S \rightarrow \pi^0 \pi^0$ )

Error on  $K_S K$  down from 18% to 6% (CLEO-c [1])

$\Rightarrow$  Can determine the  $B(D_s^+ \rightarrow \tau^+ \nu_\tau)$  by using the known  $B(D_s^+ \rightarrow K_S K^+)$

$$B(D_s^+ \rightarrow \tau^+ \nu_\tau) \Rightarrow \frac{N_{\tau\nu}}{N_{K_S K}} \frac{B(D_s^+ \rightarrow K_S K^+)}{B(\tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau)}$$

Can then extract  $f_{D_s}$  using:

$$f_{D_s} = \sqrt{\frac{\Gamma(D_s^+ \rightarrow \tau^+ \nu_\tau)}{\frac{G_F^2}{8\pi} \left(\frac{m_\tau}{m_{D_s}}\right)^2 \left(1 - \frac{m_\tau^2}{m_{D_s}^2}\right)^2 |V_{cs}|^2}}$$

# Signal Event Selection

- **Blind Analysis**
  - 427 fb<sup>-1</sup> Runs 1-6 On-Peak Data
- $D_s^* \rightarrow D_s \gamma$ ,  $D_s \rightarrow \tau \nu$  from continuum  $c\bar{c}$  events
- Charm Tagged
- Fully Reconstructed Event
- Yield Extraction:
  - 2-D Fit
    - $D_s$  Recoil Mass
    - Extra Energy of the Event

$$e^+ e^- \rightarrow c\bar{c}$$

$$c\bar{c} \rightarrow D_{Tag} D_s^* K(X)$$

Pions From  
Fragmentation

$$D_s^* \rightarrow D_s \gamma$$

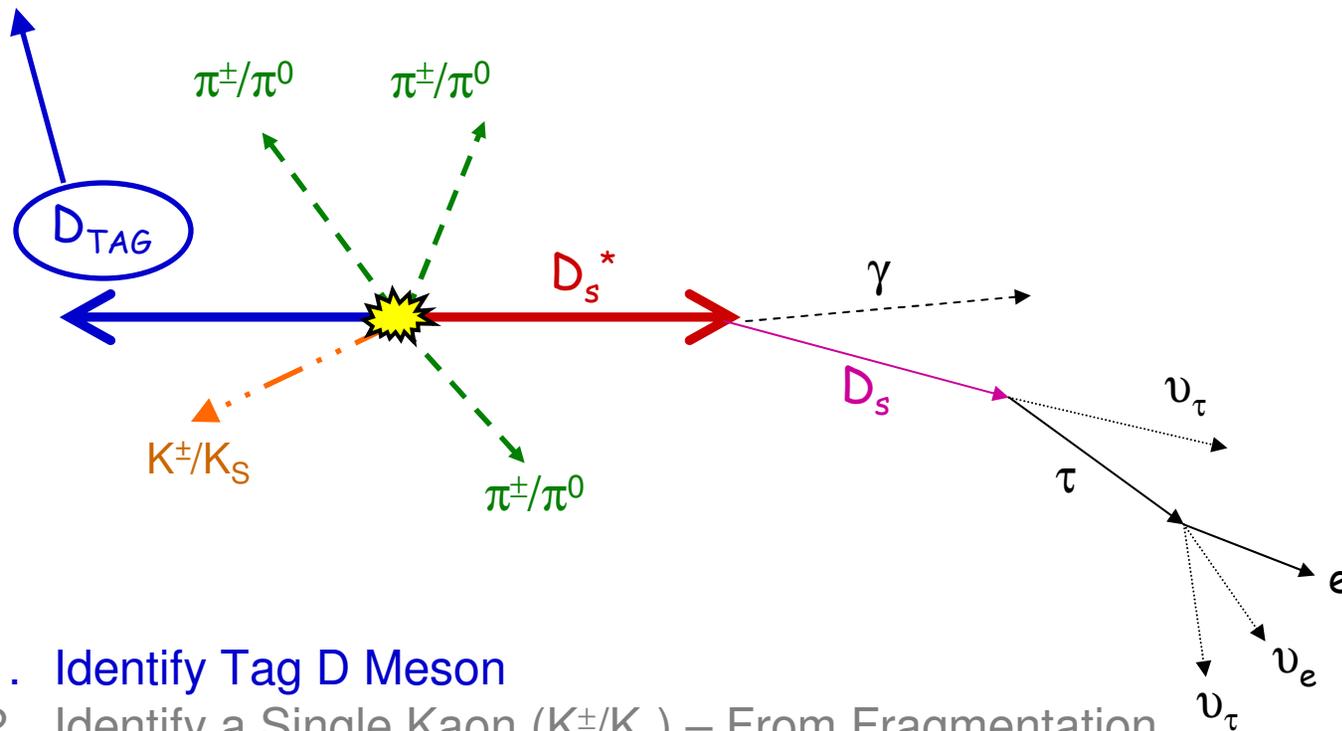
$$D_s \rightarrow \tau \nu_\tau$$

$$\tau \rightarrow e \nu_e \nu_\tau$$

# Signal Event Selection

$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$

## Tag D Meson ( $D^0, D^\pm$ ) – Reconstructed From Multiple Decay Modes



- ➔
1. Identify Tag D Meson
  2. Identify a Single Kaon ( $K^\pm/K_S$ ) – From Fragmentation
  3. Identify any Pions ( $\pi^\pm/\pi^0$ ) – From Fragmentation
  4. Identify the “Signal” Photon from  $D_s^* \rightarrow D_s \gamma$

# Charm Tagging Decay Modes

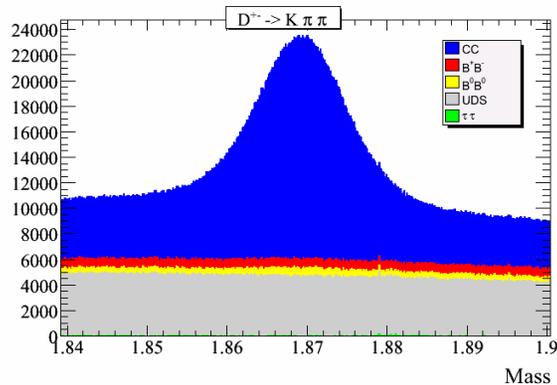
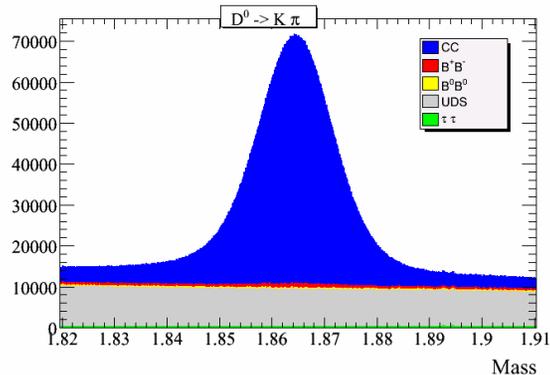


Table 6: Charm Tag Modes

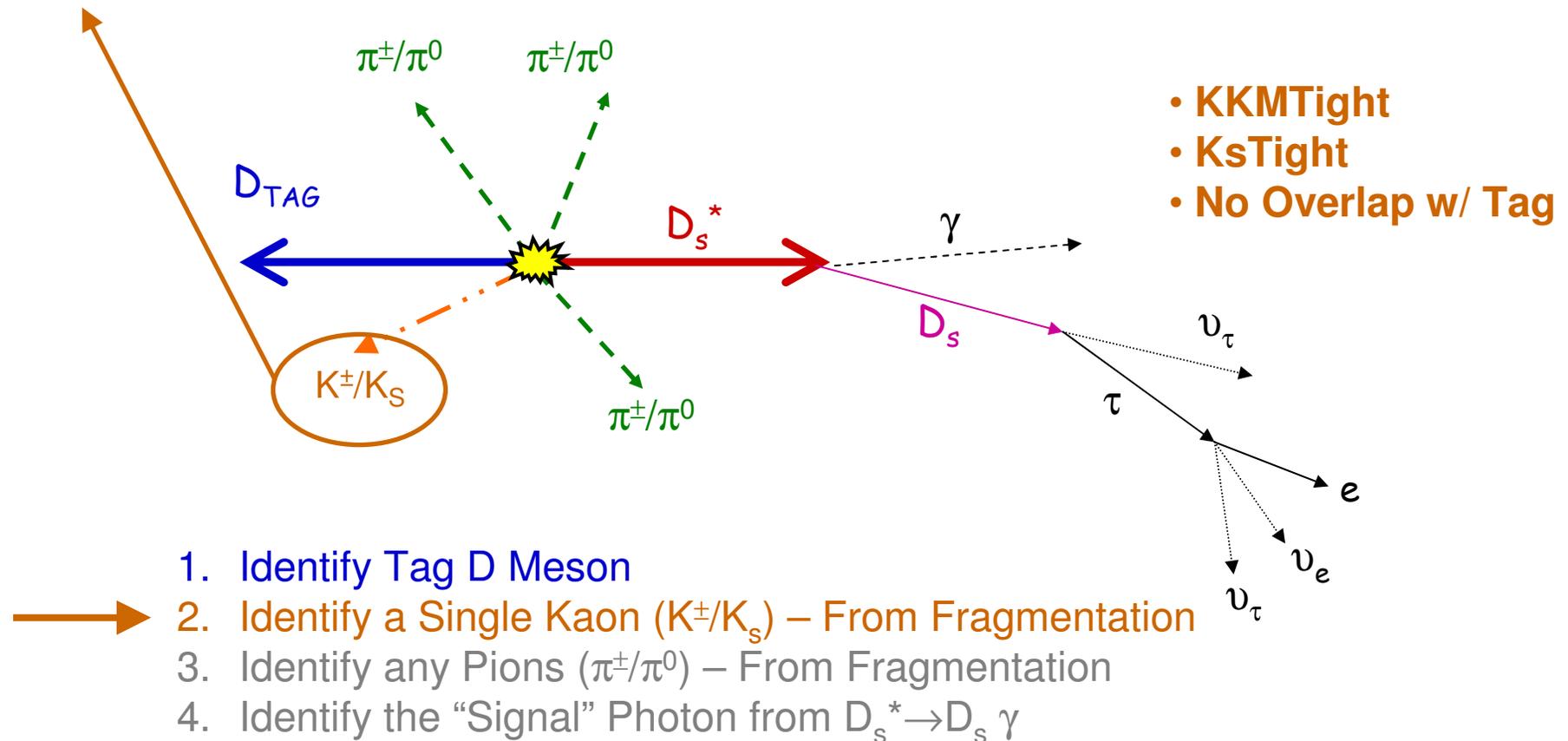
Index	Decay Mode	Branching Fraction(%)
1	$D^0 \rightarrow K\pi$	$3.80 \pm 0.07$
2	$D^0 \rightarrow K\pi\pi^0$	$14.1 \pm 0.5$
3	$D^0 \rightarrow K\pi\pi\pi$	$7.72 \pm 0.28$
4	$D^0 \rightarrow K\pi\pi\pi\pi^0$	$4.2 \pm 0.4$
5	$D^0 \rightarrow K_S^0\pi\pi$	$2.90 \pm 0.19$
6	$D^0 \rightarrow K_S^0\pi\pi\pi^0$	$5.4 \pm 0.6$
7	$D^+ \rightarrow K\pi\pi$	$9.51 \pm 0.34$
8	$D^+ \rightarrow K\pi\pi\pi^0$	$5.5 \pm 2.7$
9	$D^+ \rightarrow K_S^0\pi$	$1.47 \pm 0.06$
10	$D^+ \rightarrow K_S^0\pi\pi^0$	$7.0 \pm 0.5$
11	$D^+ \rightarrow K_S^0\pi\pi\pi$	$3.11 \pm 0.21$

- Using the cleanest reconstructed decay modes.
- Using D modes that have the largest branching fractions
- Reconstructed Using CharmTagTools
- $p^* > 2.35$  GeV – Reduce BB background

# Signal Event Selection

$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$

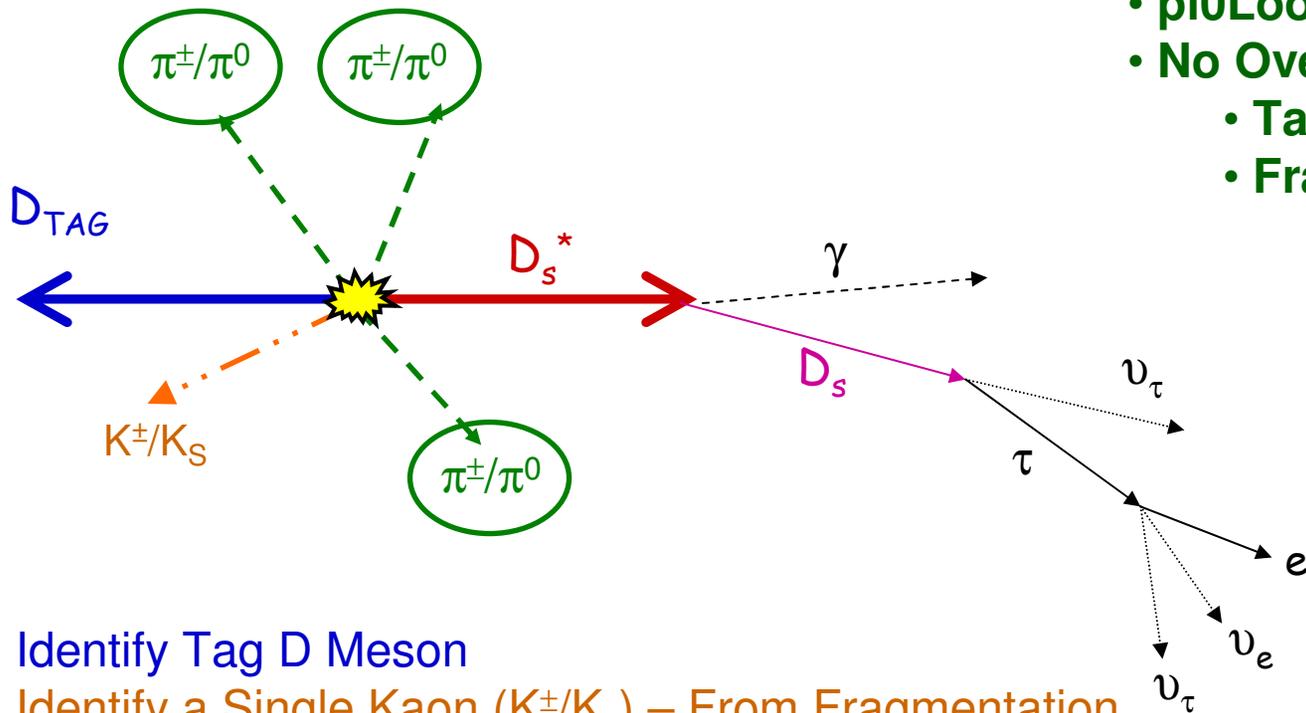
## Single Kaon from Fragmentation – Flavor Balancing (s-quark)



# Signal Event Selection

$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$

Fragmentation Pions –  $\pi^\pm/\pi^0$



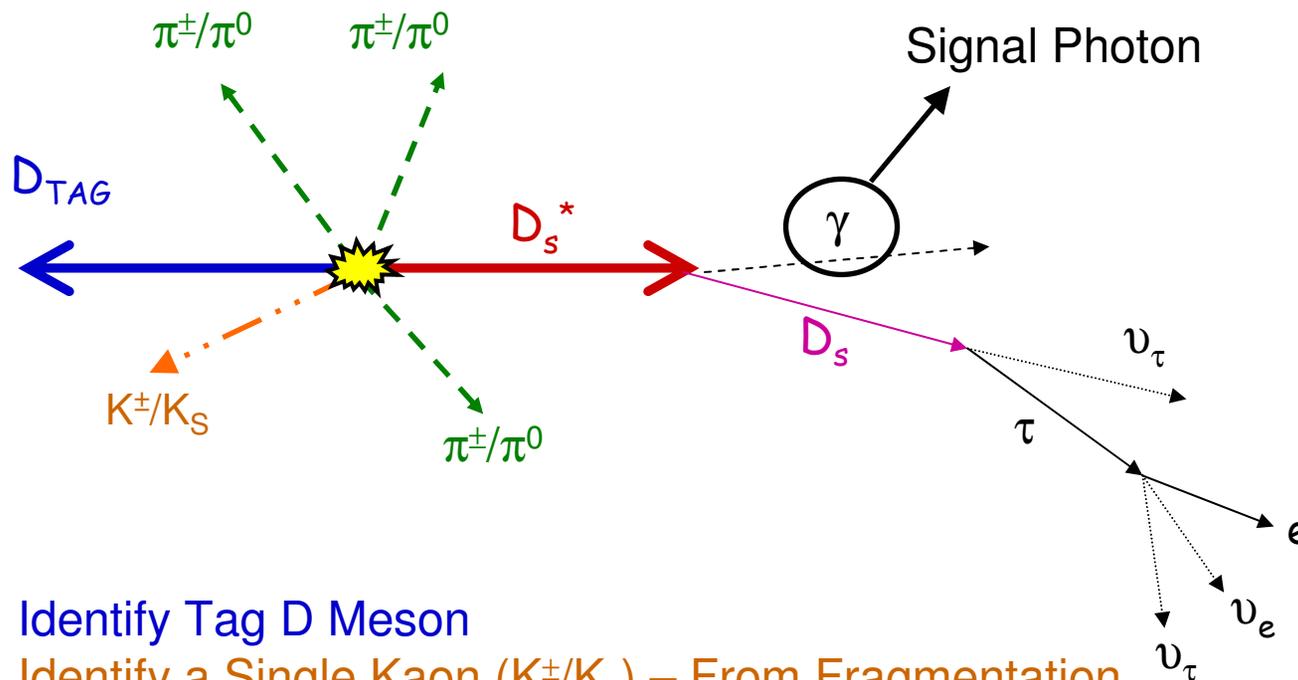
- piKMLoose
- pi0Loose
- No Overlap w/
  - Tag
  - Frag. Kaon

1. Identify Tag D Meson
2. Identify a Single Kaon ( $K^\pm/K_S$ ) – From Fragmentation
- 3. Identify any Pions ( $\pi^\pm/\pi^0$ ) – From Fragmentation
4. Identify the “Signal” Photon from  $D_s^* \rightarrow D_s \gamma$

# Signal Event Selection

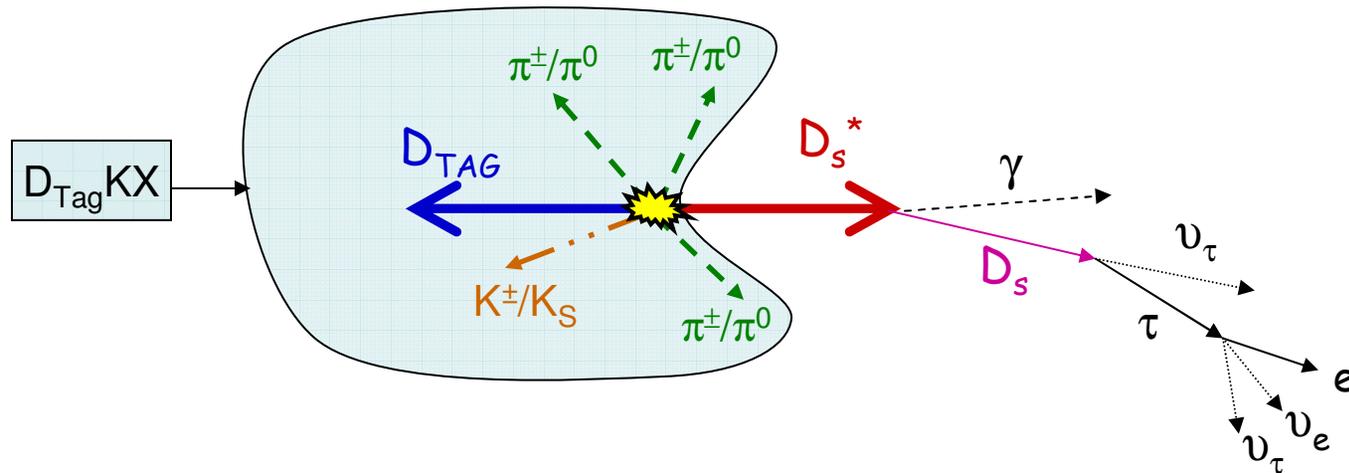
$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$

- Good Photon Loose
- $E_\gamma > 100$  MeV
- No Overlap w/
  - Tag,  $\pi^0$



1. Identify Tag D Meson
2. Identify a Single Kaon ( $K^\pm/K_s$ ) – From Fragmentation
3. Identify any Pions ( $\pi^\pm/\pi^0$ ) – From Fragmentation
- 4. Identify the “Signal” Photon from  $D_s^* \rightarrow D_s \gamma$

# Event Reconstruction Recoil Masses



A  $D_S^*$  candidate is built from the particles recoiling against it:

- $D_{TAG}$
- Fragmentation Kaon
- Fragmentation Pions – “X”
- Mass Constrained Fit
- 200 MeV Mass Window

$$D_S^* = \text{Beam} - (D_{TAG} + K + X)$$

The  $D_S^*$  candidate is combined with a “signal” photon candidate to create a  $D_S$  candidate. Correctly reconstructed events should Peak at the  $D_S$  Mass (1.968 GeV).

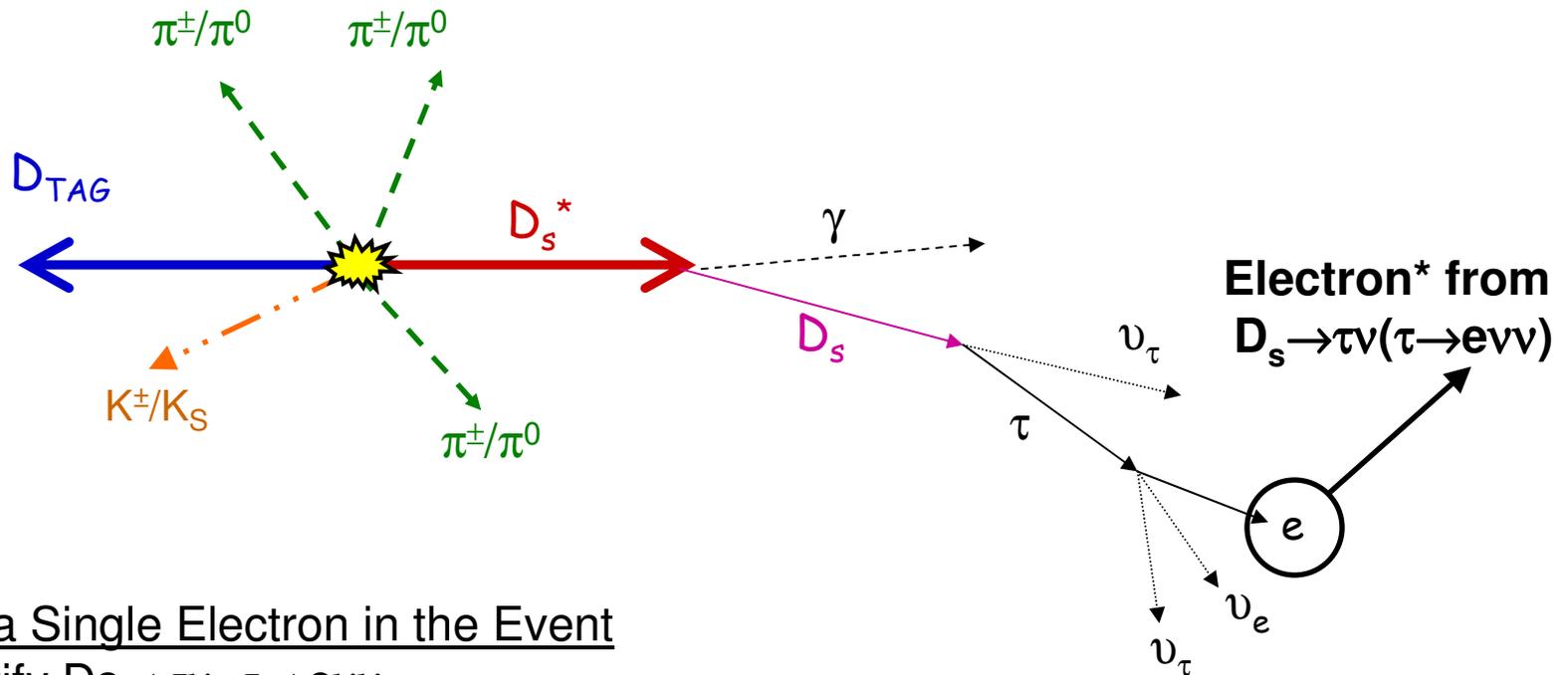
$$D_S = M_{\text{Recoil}} = D_S^* - \gamma$$

$$\text{Extra Energy} = \sum \left( \text{Any Photons Not Associated With Any of the Reconstructed Tracks, or the Signal Photon} \right)$$

# Signal Event Selection

$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$

\*Also Measuring  $D_s \rightarrow K_S K$   
 $\Rightarrow$  electron replaced by  $K_S K$  pair



## Identify a Single Electron in the Event

- Identify  $D_s \rightarrow \tau \nu$ ,  $\tau \rightarrow e \nu \nu$
- eKMVeryLoose
- No overlap w/ gammaConversionDefault
- >4 SVT Hits
- $\geq 12$  DCH Hits

# $D_s$ Recoil Mass Spectrum Signal Extraction

Many variables were investigated that would extract the signal. The largest discriminating variables are:

- $D_s^*$  Kinematic Fit Probability
- CM Momentum of the  $D_s$

- **Optimization Method for Cut Variables**

- Optimized on MC
- Repeated for Multiple  $D_s$  Mass Windows
  - 10-200MeV
- Both Methods Return Similar Results

- **1 – Optimization Package: SprBumpHunter**

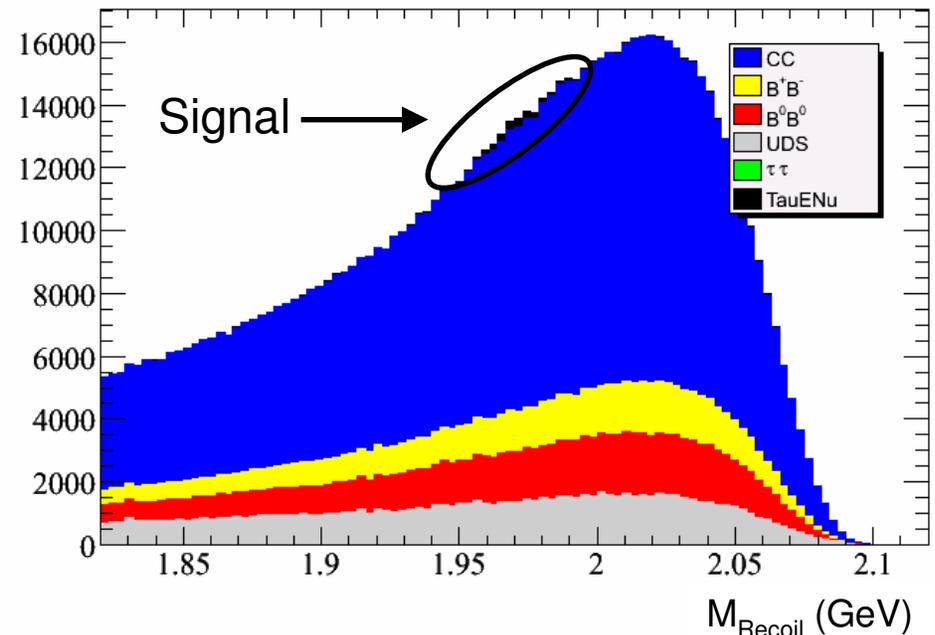
- Searches for rectangular region w/ globally optimized FOM ( $S/\sqrt{S+B}$ )
- Training/Validation Samples
  - 20:80 50:50 80:20

- **2 - Iterative Optimization**

- Randomly/Progressively Choose and Optimize Cut Variables according to FOM

## Run 1-6 Monte Carlo

(Normalized to 427 fb<sup>-1</sup>)



# Monte Carlo - Event Selection Variables

## Recoil $D_s$ CM Momentum

ccbar Monte Carlo

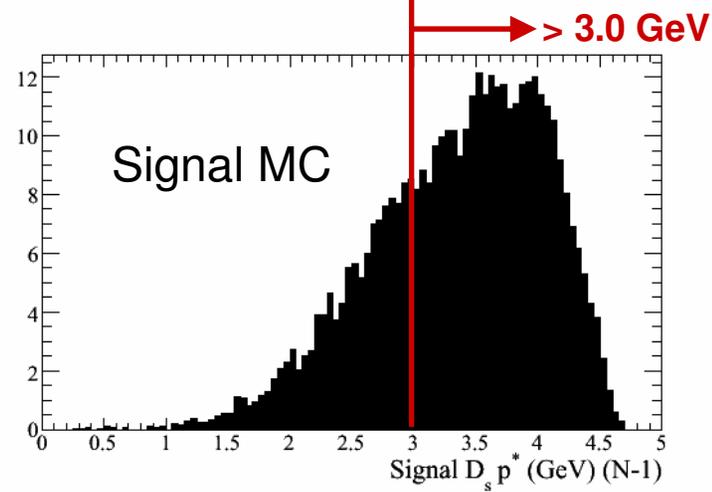
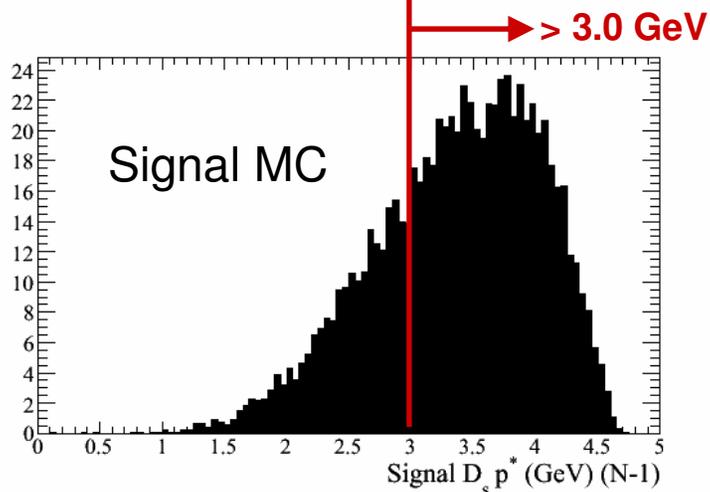
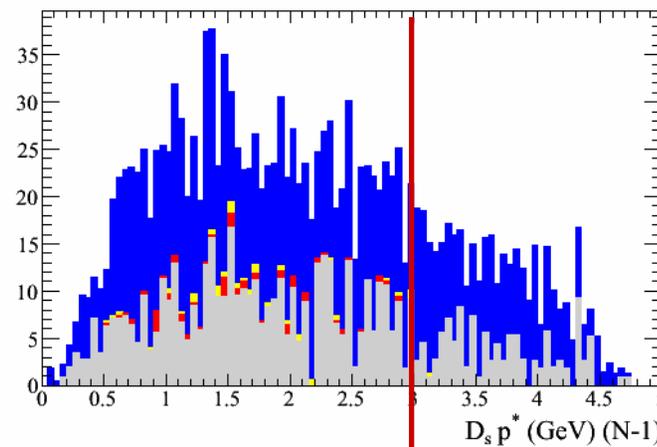
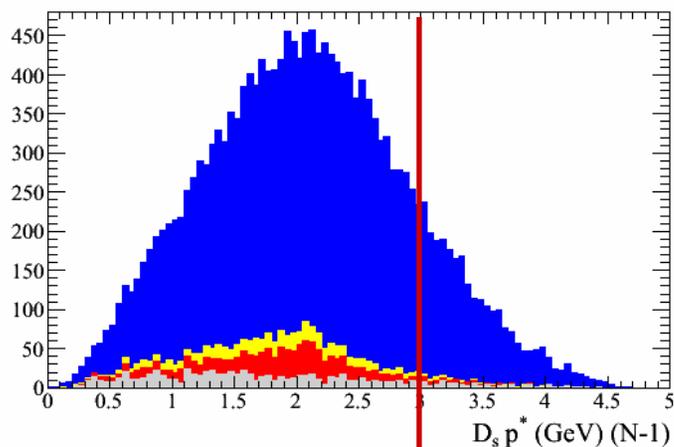
B<sup>+</sup>B<sup>-</sup> Monte Carlo

uds Monte Carlo

B<sup>0</sup>B<sup>0</sup> Monte Carlo

$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$

$$D_s^+ \rightarrow K_S K^+ : K_S \rightarrow \pi^+ \pi^-$$



# Monte Carlo - Event Selection Variables

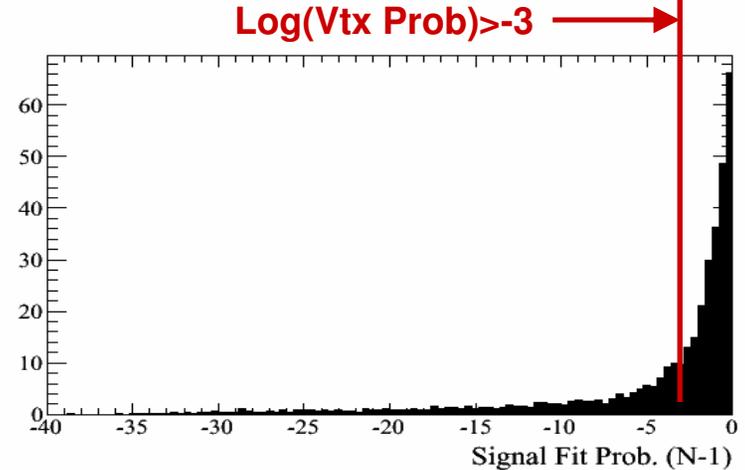
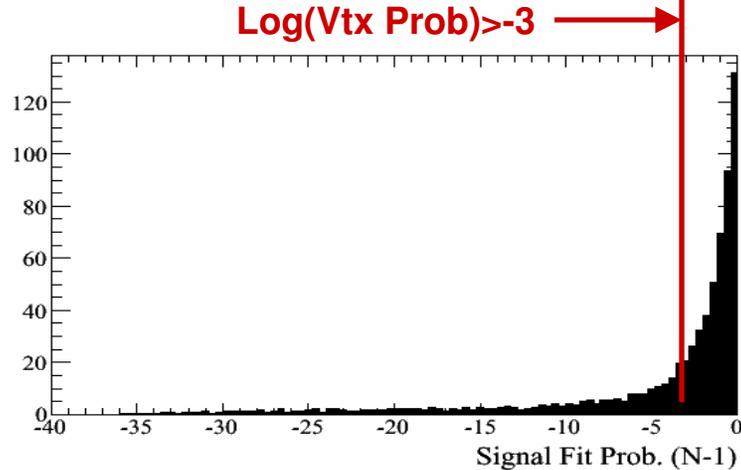
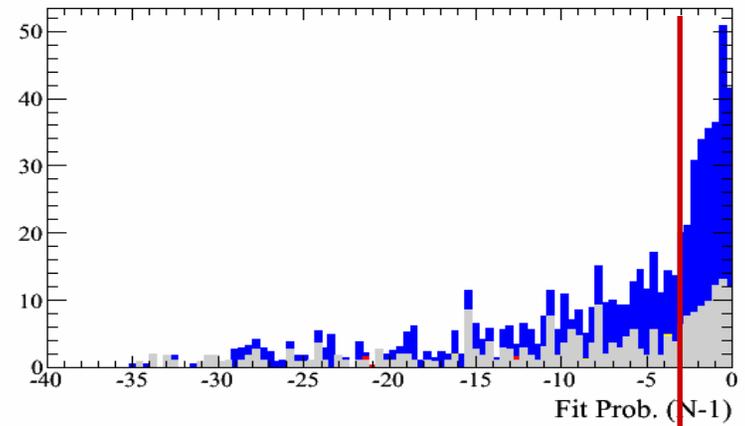
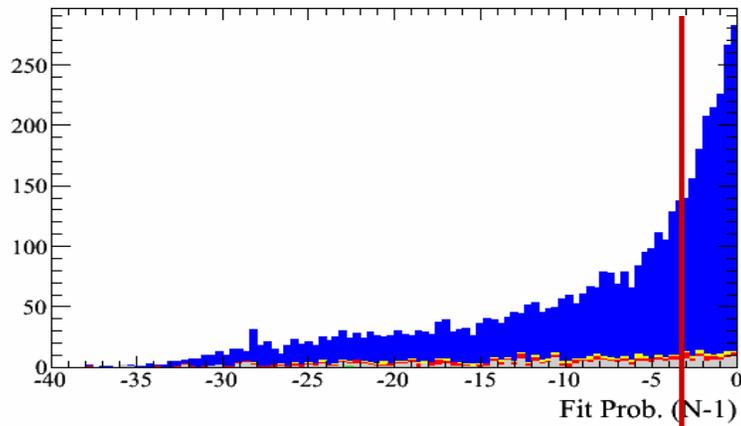
## Recoil $D_s^*$ Kinematic Fit Probability

ccbar Monte Carlo  
uds Monte Carlo

B<sup>+</sup>B<sup>-</sup> Monte Carlo  
B<sup>0</sup>B<sup>0</sup> Monte Carlo

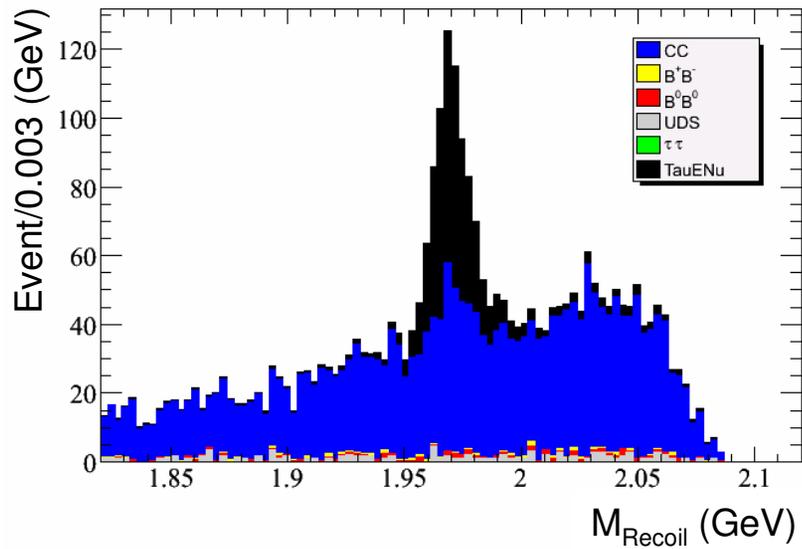
$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$

$$D_s^+ \rightarrow K_S K^+ : K_S \rightarrow \pi^+ \pi^-$$

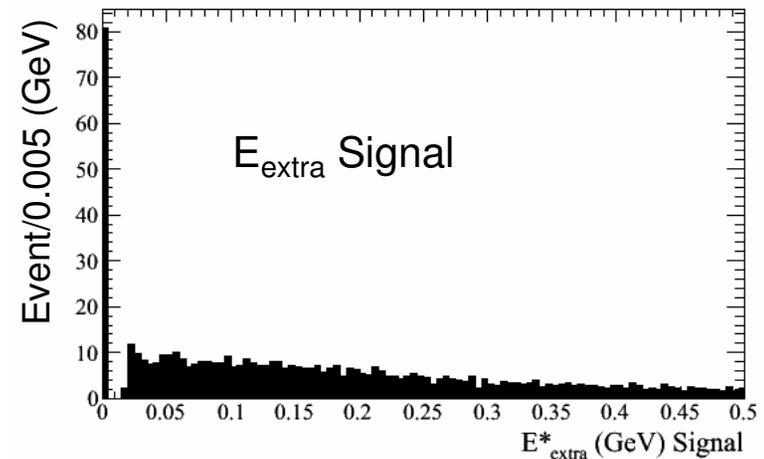
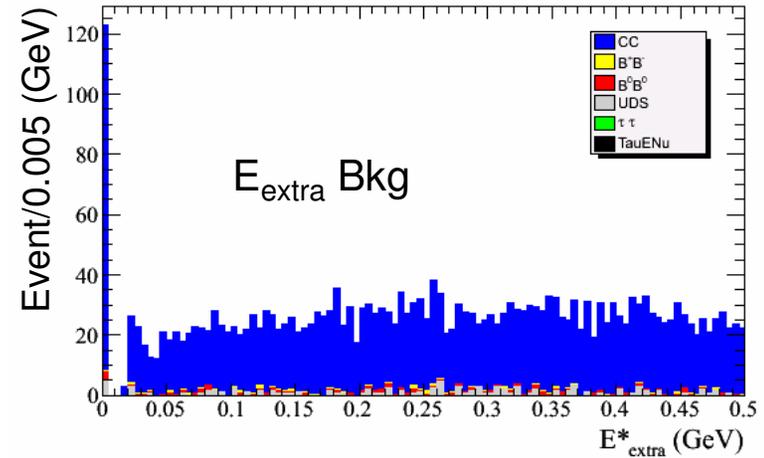


# Reconstructed $D_s$ Mass and Extra Energy Monte Carlo - Normalized to $427 \text{ fb}^{-1}$

$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$

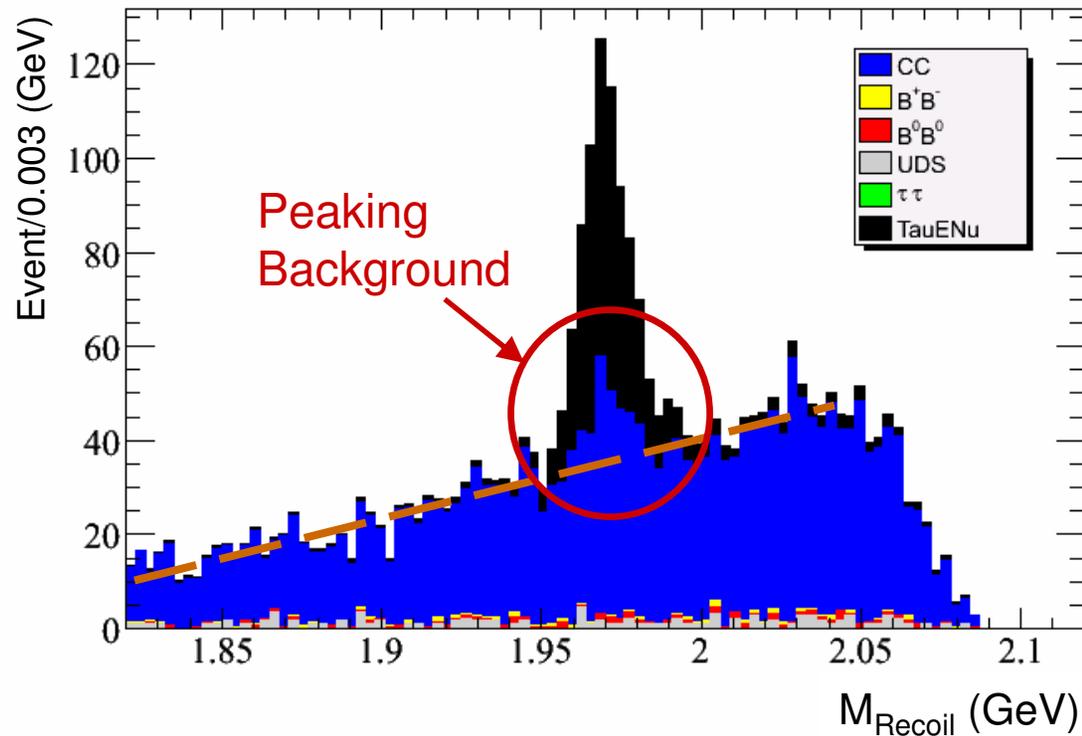


Expected MC Yields:  
 Total Signal = 566  
 Total Background = 2145  
 Total Peak Background = 385



# Reconstructed $D_s$ Mass and Extra Energy Monte Carlo - Normalized to $427 \text{ fb}^{-1}$

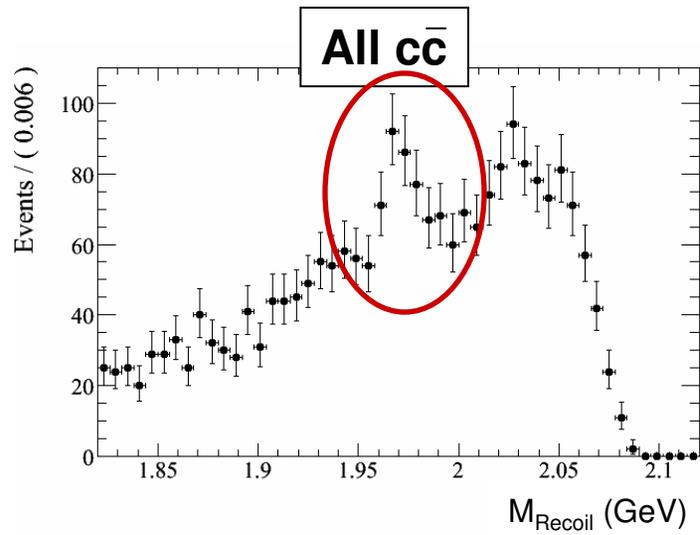
$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$



**Clearly a peaking background  
component from cc events  
What are the modes?  
What are the expected yields?**

# Peaking Background Modes

## Monte Carlo – Normalized to 427 fb<sup>-1</sup>



**Dominant Modes**  
**In 10MeV Mass Window Around**  
**the  $D_s$  Mass in  $cc$  sample:**

$D^0$

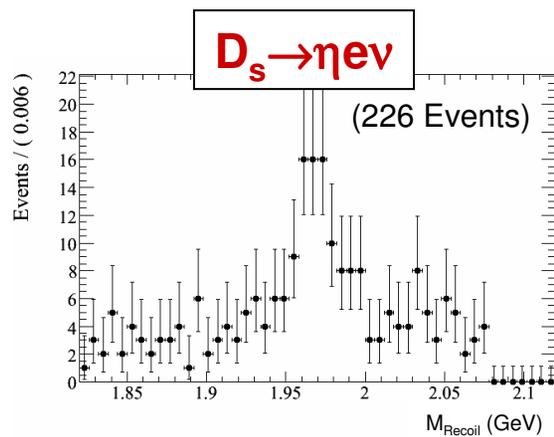
- $K e \nu$
- $K^* e \nu$

$D^+$

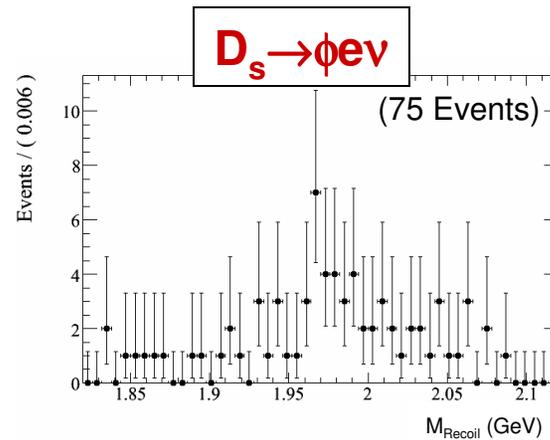
- $K^0 e \nu$
- $K^{*0} e \nu$

$D_s$

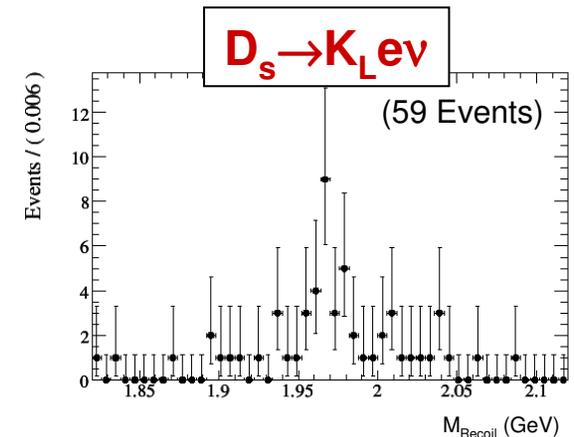
- $\eta e \nu$
- $\eta' e \nu$
- $\phi e \nu$
- $K_L e \nu$



$$BF = (2.9 \pm 0.6)\%$$



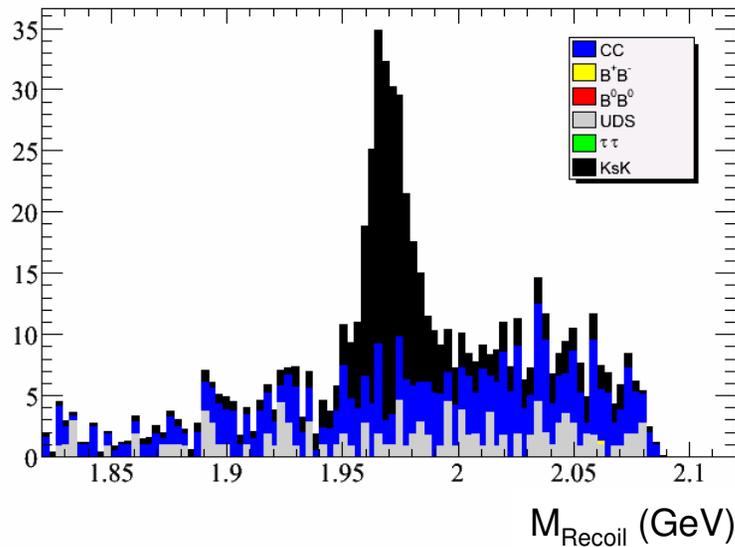
$$BF = (2.36 \pm 0.26)\%$$



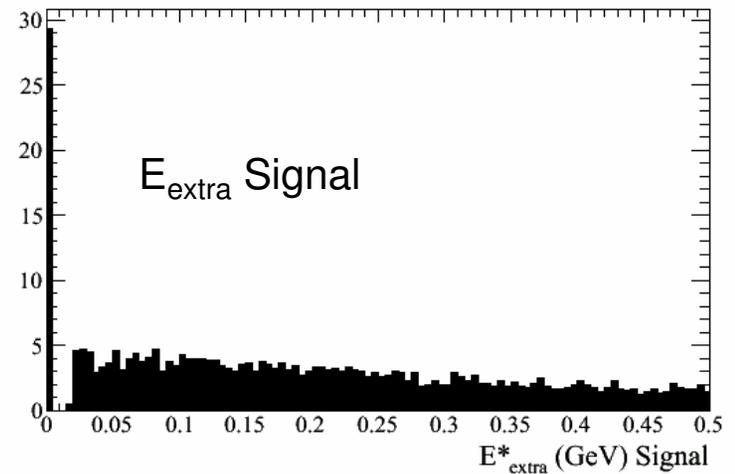
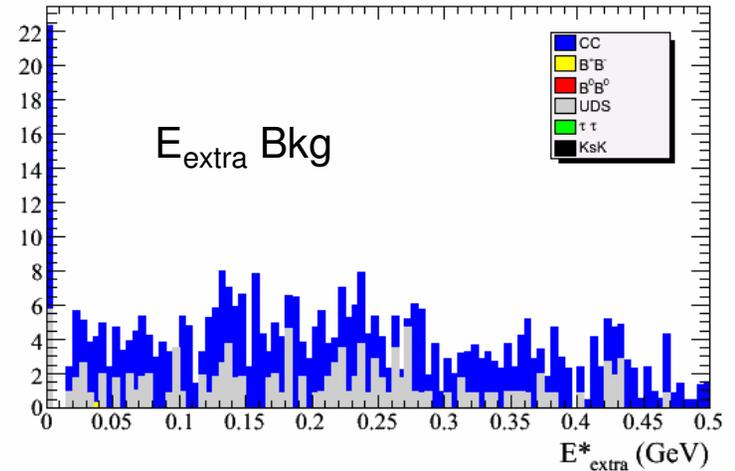
$$BF = (0.19 \pm 0.05)\%$$

# Reconstructed $D_s$ Mass and Extra Energy Monte Carlo - Normalized to 427 fb<sup>-1</sup>

$$D_s^+ \rightarrow K_S K^+ : K_S \rightarrow \pi^+ \pi^-$$

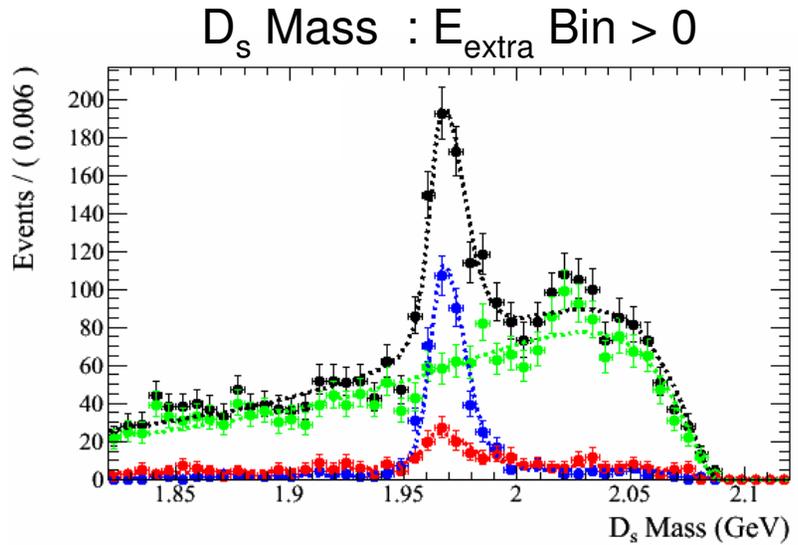


MC Yields:  
 Total Signal = 289  
 Total Background = 380



# Toy Monte Carlo Study

All  
Signal  
Background  
Peaking Background

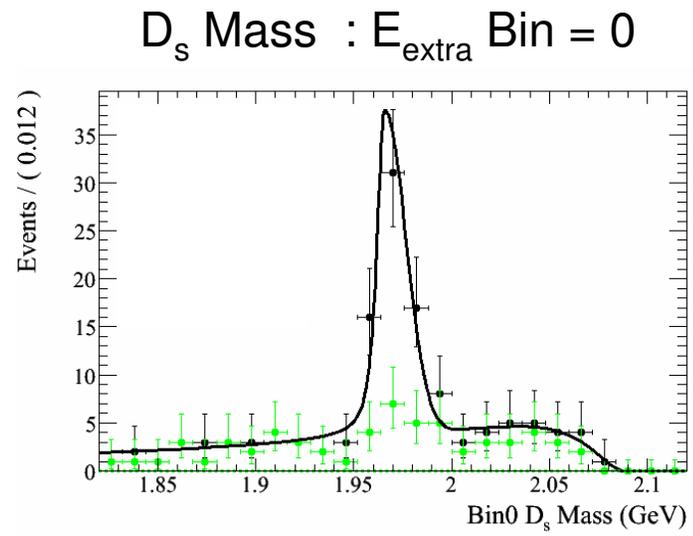
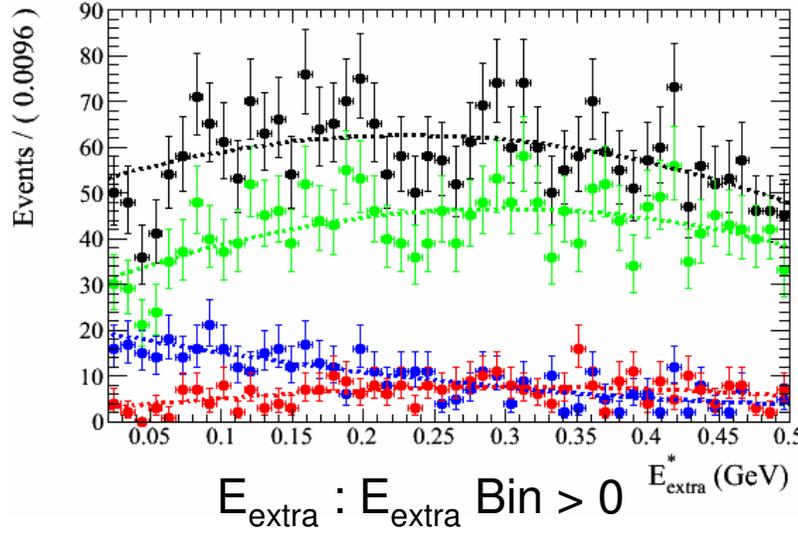


- Signal - PDF's**
- $D_s$  Mass – Cruiff\* + Novosibirsk
  - $E_{extra}$  - Poly
- Background - PDF's**
- $D_s$  Mass - Novosibirsk
  - $E_{extra}$  - Novosibirsk
- Peaking Background - PDF's**
- $D_s$  Mass – Cruiff\* + Novosibirsk
  - $E_{extra}$  - Poly



J. Cruiff

2D - Fit



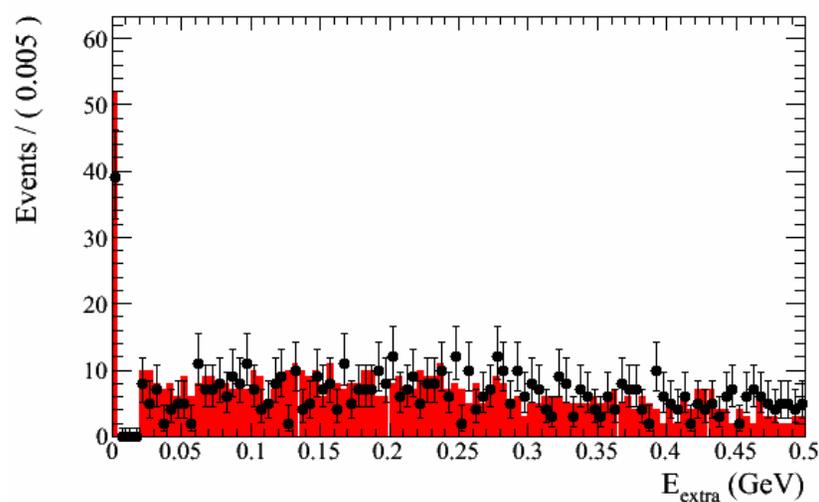
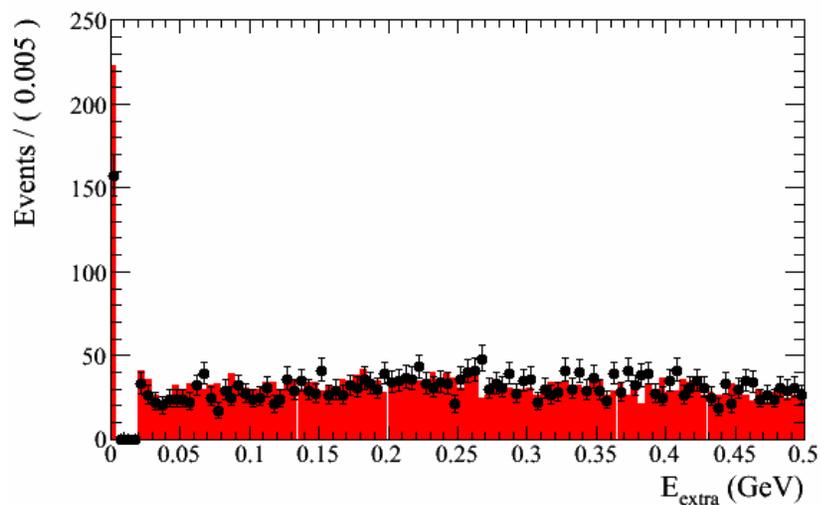
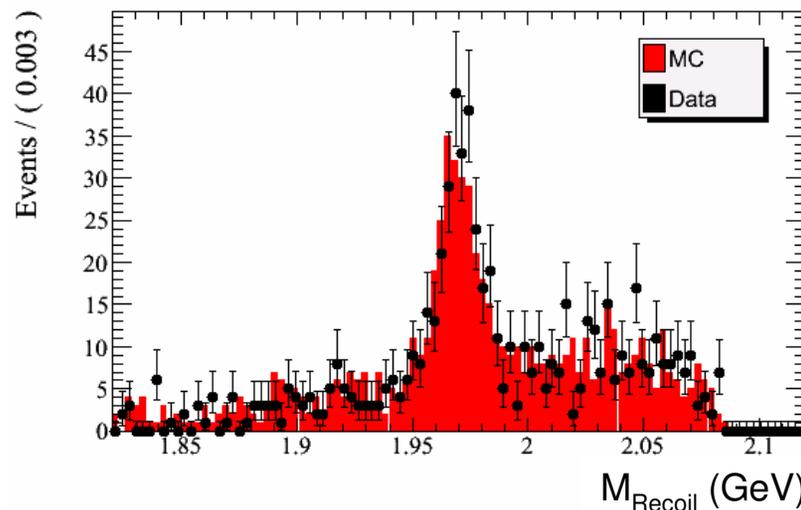
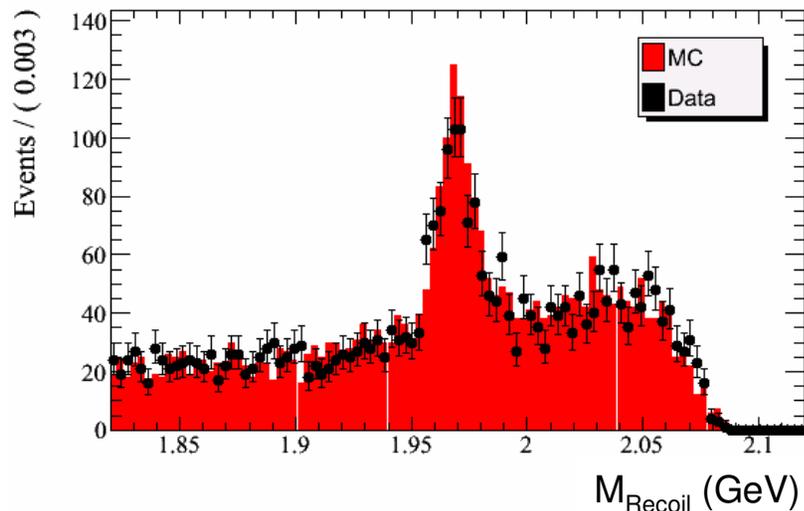
\*Cruiff PDF – Crystal Ball w/ Separate Left and Right Sides

# Data vs MC - $D_s$ Recoil Mass & Extra Energy

## Runs 1-6 On-Peak 427 fb<sup>-1</sup>

$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$

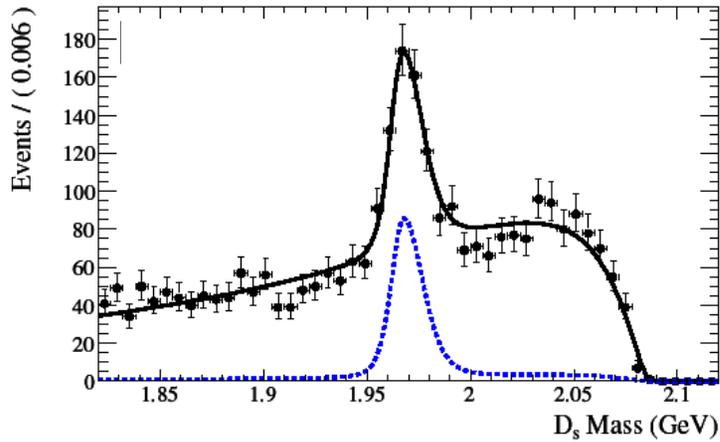
$$D_s^+ \rightarrow K_S K^+ : K_S \rightarrow \pi^+ \pi^-$$



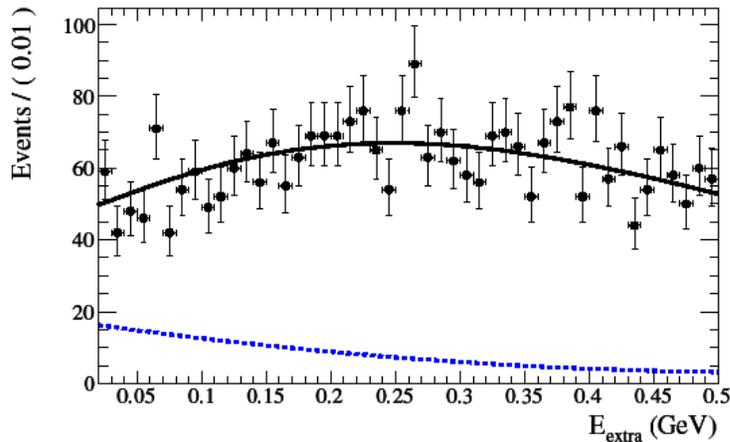
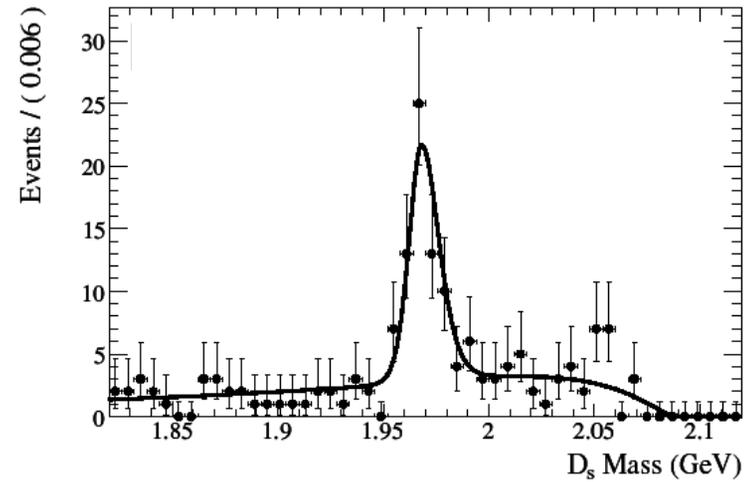
# Fits to Data

$$D_s^+ \rightarrow \tau^+ \nu_\tau : \tau^+ \rightarrow e^+ \nu_e \bar{\nu}_\tau$$

$D_s$  Mass :  $E_{\text{extra}}$  Bin > 0



$D_s$  Mass :  $E_{\text{extra}}$  Bin = 0



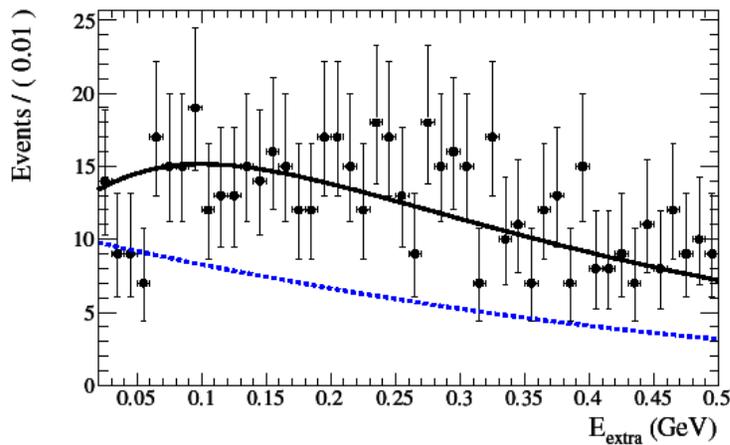
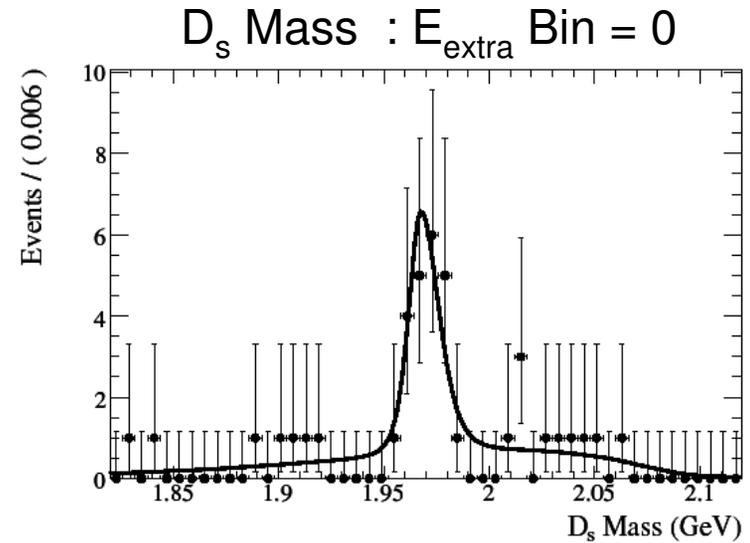
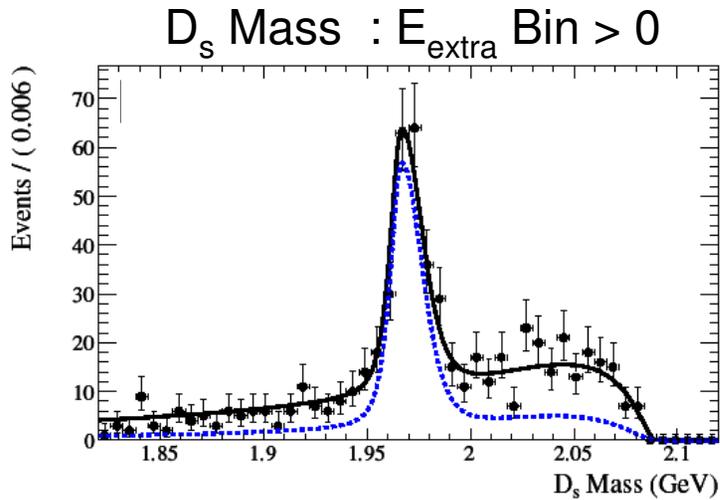
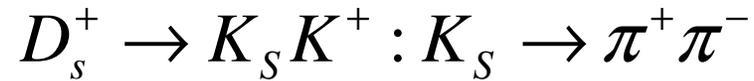
The solid curve is the fit to data.  
The dashed curve is the signal contribution.

**Total Yields:**

$$N_{\text{Sig}} = 448 \pm 36$$

$$N_{\text{Bkg}} = 2264 \pm 58$$

# Fits to Data



The solid curve is the fit to data.  
The dashed curve is the signal contribution.

## Total Yields:

$$N_{\text{Sig}} = 332.5 \pm 27.7$$

$$N_{\text{Bkg}} = 305.5 \pm 27.5$$

# Systematics Uncertainties

$$\frac{B(D_s \rightarrow \tau \nu_\tau)}{B(D_s \rightarrow K_s K)} \Rightarrow \frac{B(K_s \rightarrow \pi^+ \pi^-)}{B(\tau \rightarrow e \nu_e \nu_\tau)} \frac{N_{\tau \nu}}{N_{K_s K}} \frac{\mathcal{E}_{Cuts}^{K_s K}}{\mathcal{E}_{Cuts}^e} \frac{\mathcal{E}_{PID}^{K_s K}}{\mathcal{E}_{PID}^e} \frac{\mathcal{E}_{Trk}^{K_s K}}{\mathcal{E}_{Trk}^e}$$

## Sources of Systematic Errors:

Branching Fraction Errors

World Averages From PDG

Tracking Efficiency: MC corrected to Match Data

Cut Variables Used (MC vs Data) vs Mode

Particle Identification: Is the Electron a True Electron...

PDF Shapes: What effects do the PDF parameters have on NSig

The uncertainty on the PDF variables for  $D_s \rightarrow \tau \nu_\tau$  dominate, followed by the uncertainty on the  $D_s \rightarrow K_s K$  branching fraction. The uncertainties on the tracking and  $K_s \rightarrow \pi \pi / \tau \rightarrow e \nu_e \nu_\tau$  are negligible.

Source	Value
$B(D_s \rightarrow K_s K)$	6.0%
$B(K_s \rightarrow \pi \pi)$	0.1%
$B(\tau \rightarrow e \nu \nu)$	0.3%
Selection Variables	3.0%
Particle Identification	0.82%
Tracking	2×0.34%
$\tau \nu$ PDF Variables	+7.69% -4.73%
$K_s K$ PDF Variables	+4.86% -0.63%

# Results

$$B(D_s \rightarrow \tau \nu) = (4.54 \pm 0.53 \pm 0.40 \pm 0.28) \%$$

$$f_{D_s} = (233.6 \pm 13.6 \pm 10.4 \pm 7.1) \text{ MeV}$$

(Tot. Error = 7.9%)

Errors: Statistical  $\pm$  BaBar Systematic  $\pm$  PDG Systematic

## Results from $D_s \rightarrow \mu \nu_\mu$ measurements:

CLEO-c:  $(257.6 \pm 10.3 \pm 4.3) \text{ MeV}$   
(Tot. Error = 4.3%)

Belle:  $(275 \pm 16 \pm 12) \text{ MeV}$   
(Tot. Error = 7.3%)

## Results from $D_s \rightarrow \tau \nu_\tau$ measurements:

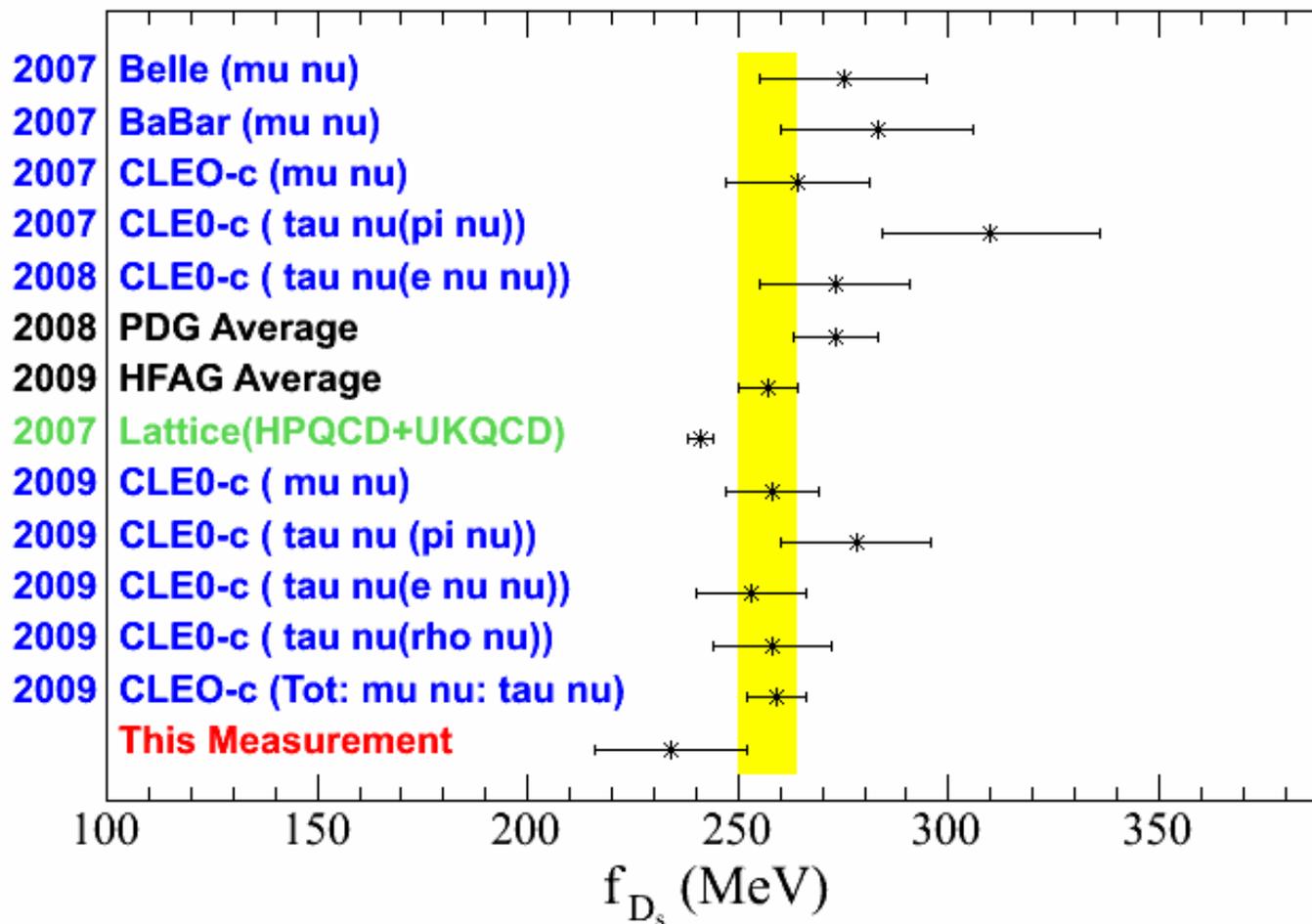
CLEO-c:  $(\tau \rightarrow \pi \nu_\tau) (278.0 \pm 17.5 \pm 4.4) \text{ MeV}$   
(Tot. Error = 6.6%)

CLEO-c:  $(\tau \rightarrow e \nu_e \nu_\tau) (252.6 \pm 11.2 \pm 5.6) \text{ MeV}$   
(Tot. Error = 4.9%)

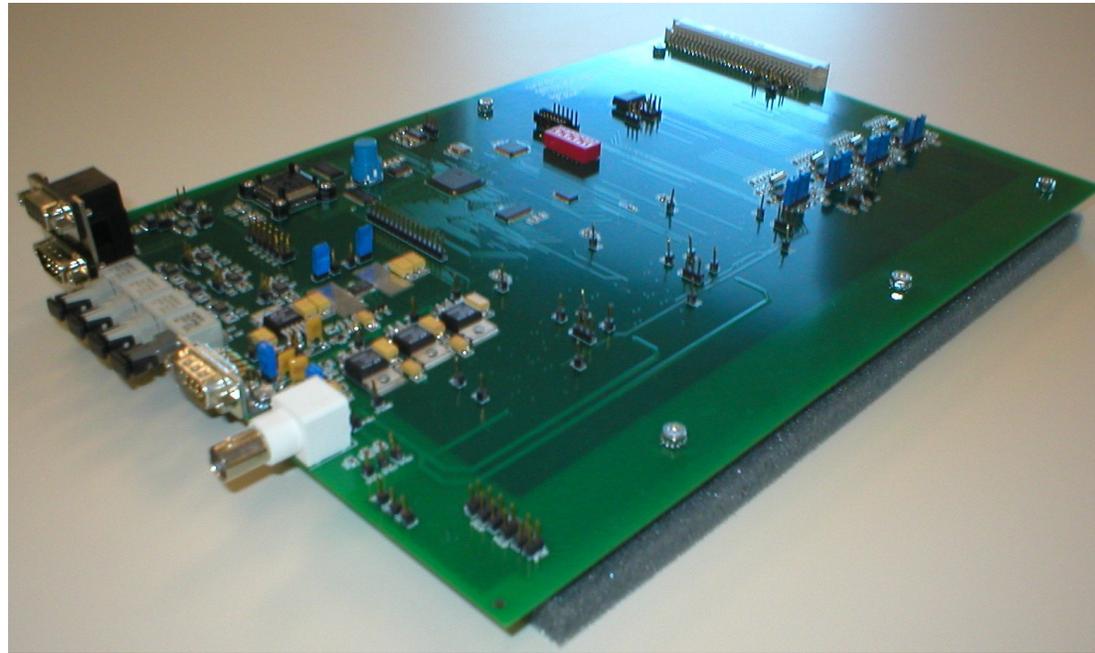
Errors: Statistical  $\pm$  Systematic

# Backup Slides

# Summary of $f_{D_s}$ Results

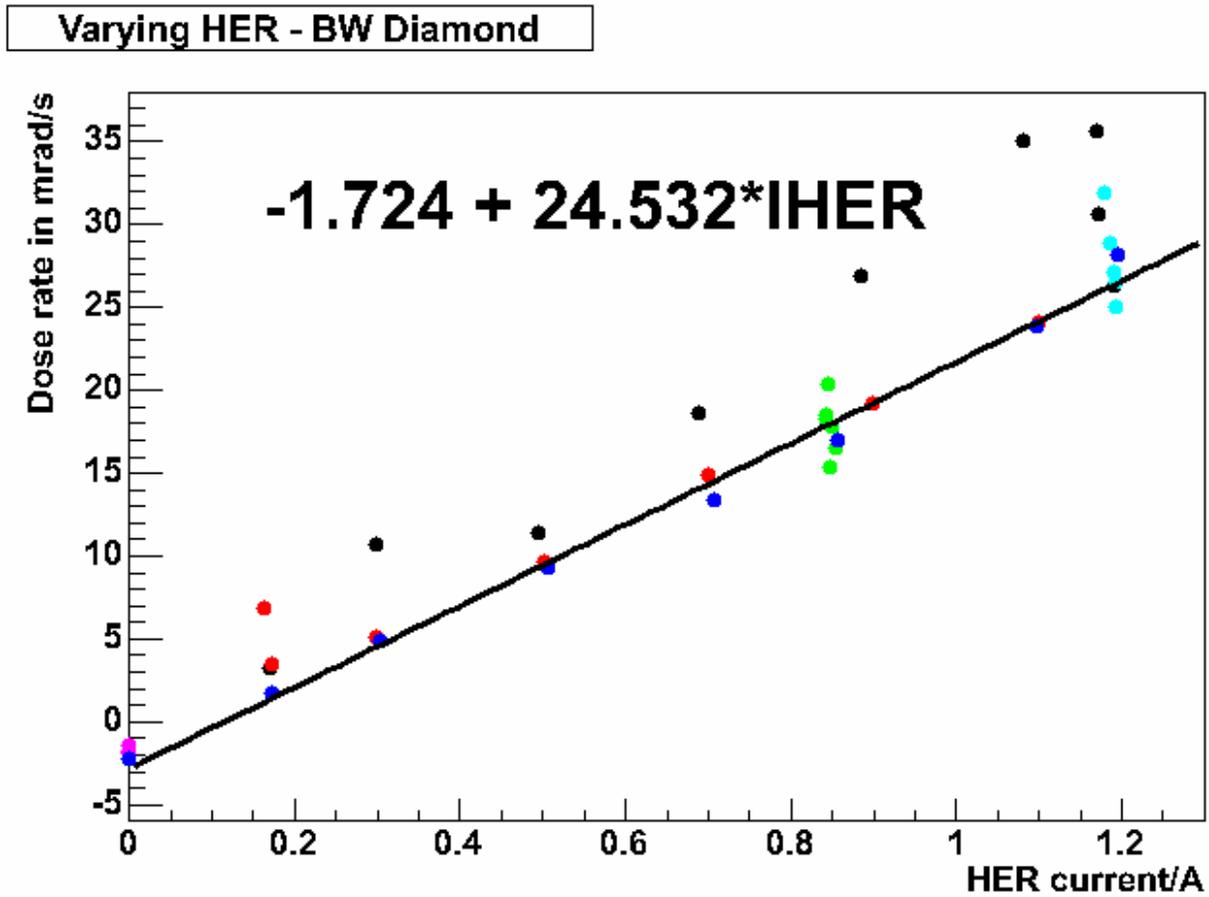


# SVTRad Electronics



- DC Coupled Readout
- $\approx 1\text{ms}$  Sampling Rate
- Monitors Total (Leakage + Radiation) Current
- Large Leakage Current Subtraction with Temperature Corrections (2 Thermistors per Diode)
- $1\text{nA} \approx 5 \text{ mRad/s}$
- Trigger Beam Dumps When Dose Rate Exceeds Maximum Allowed
- Dose Rates Read Out via CANBUS

Expected background as a function of currents and luminosity

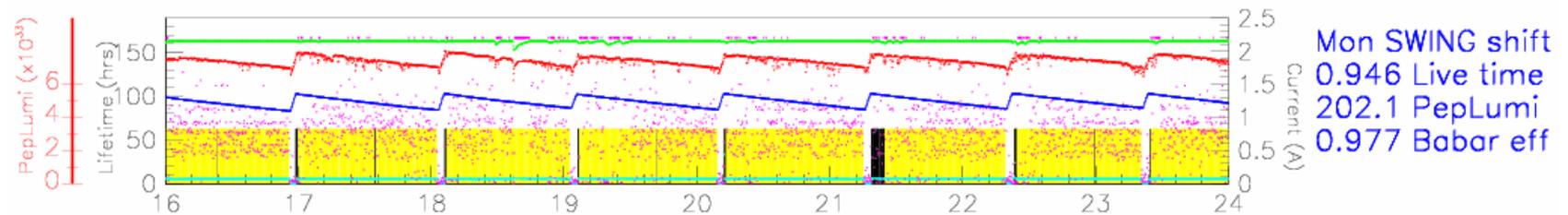


# Run 4 Progress: Trickle Injection (IV)

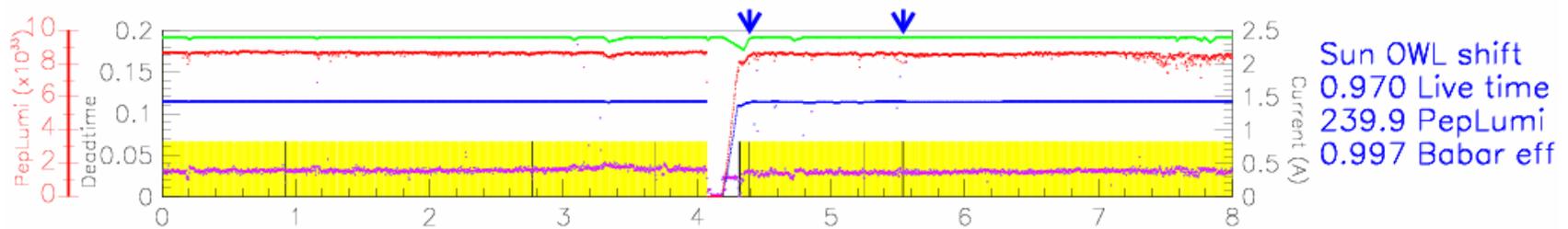
Best shift, no trickle



Best shift, LER only trickle

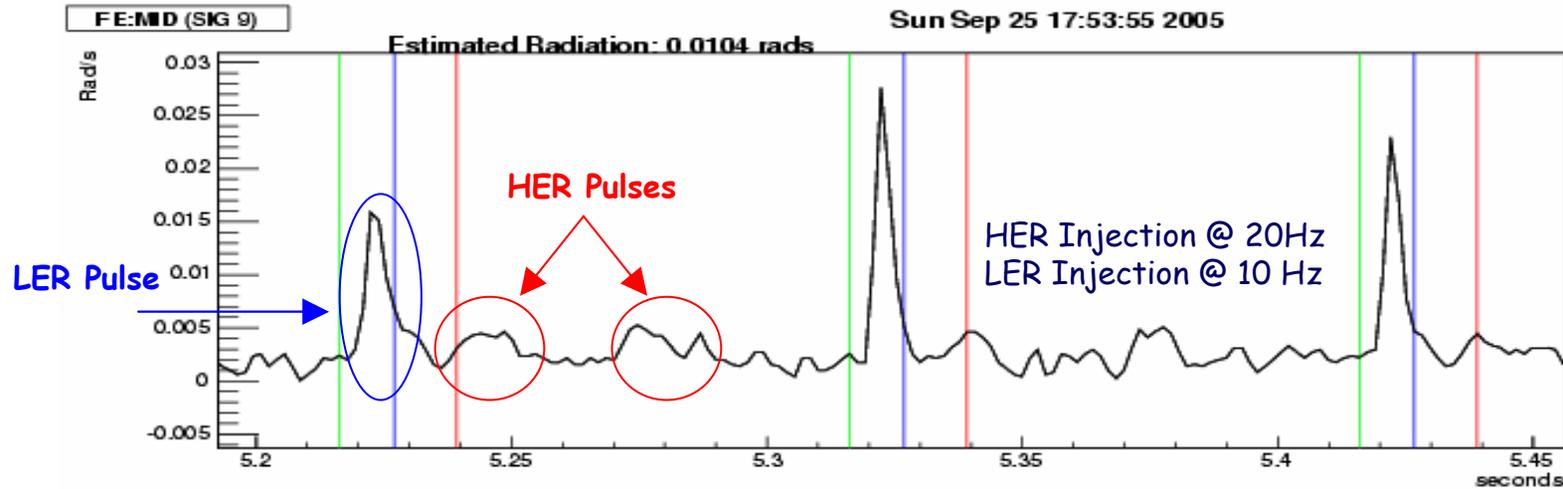


Best shift, double trickle

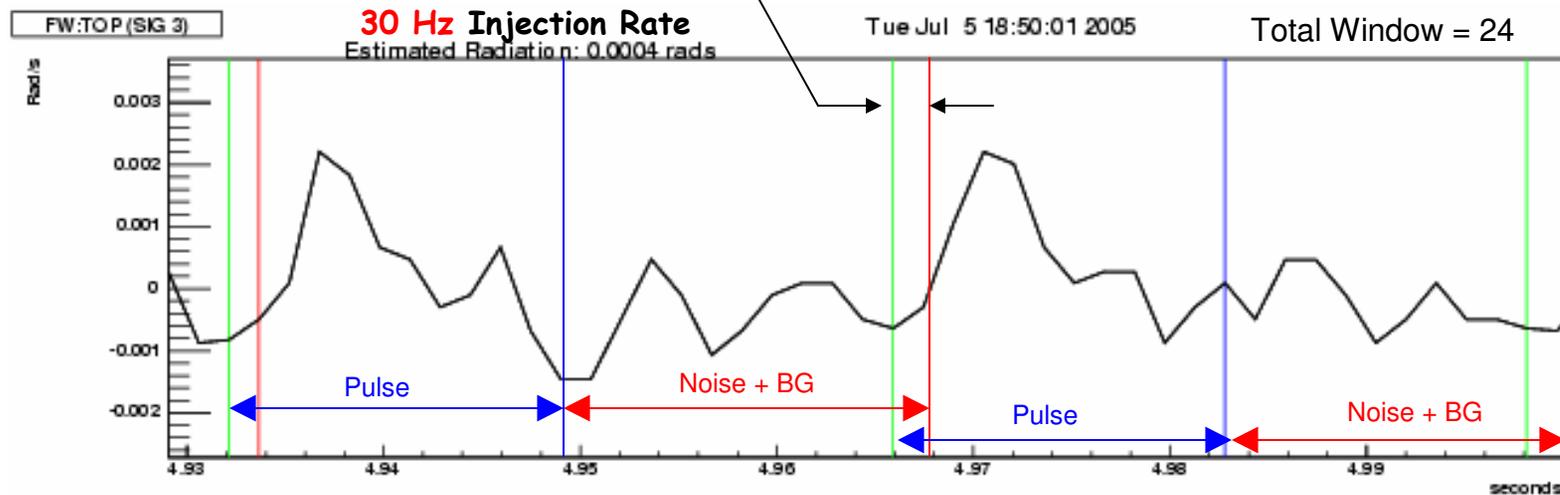


# Trickle Monitoring Limitations

- Integration will Include HER Pulse if Window (Number of Data Samples) too Wide

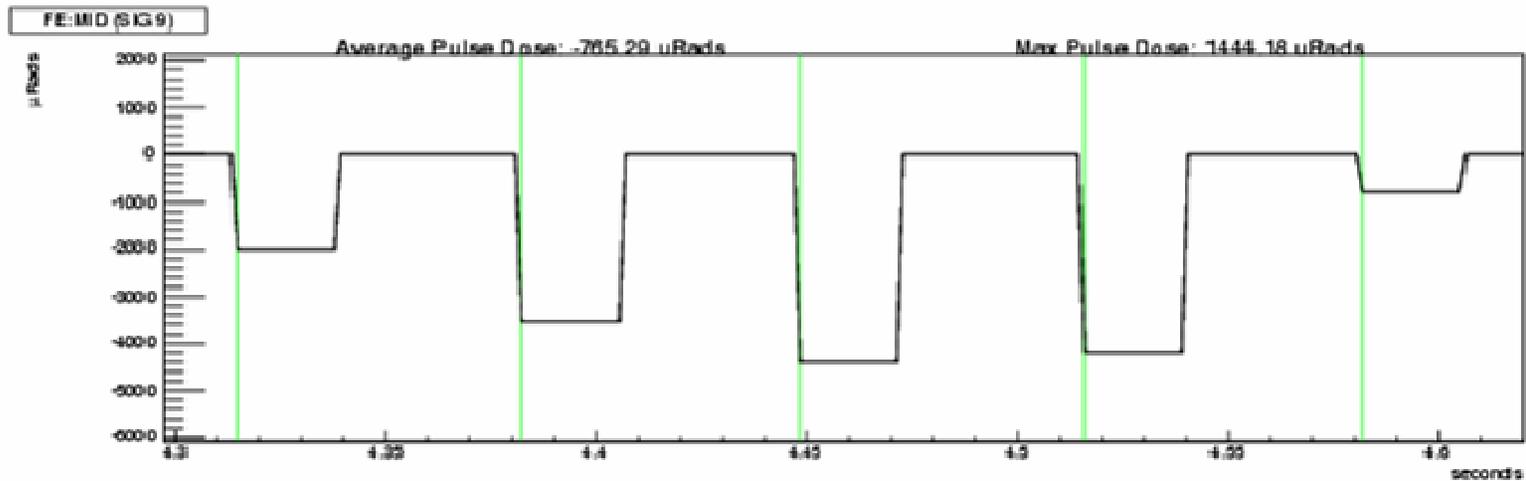
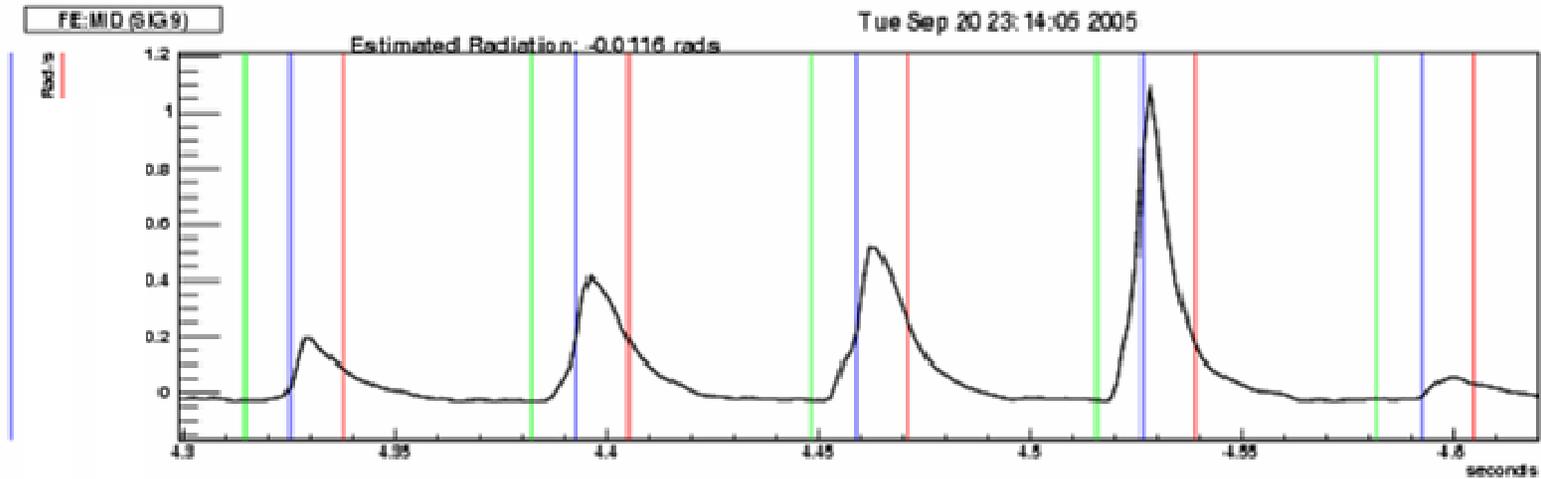


- Integration Overlaps next Pulse if Total Window > 22 Data Samples

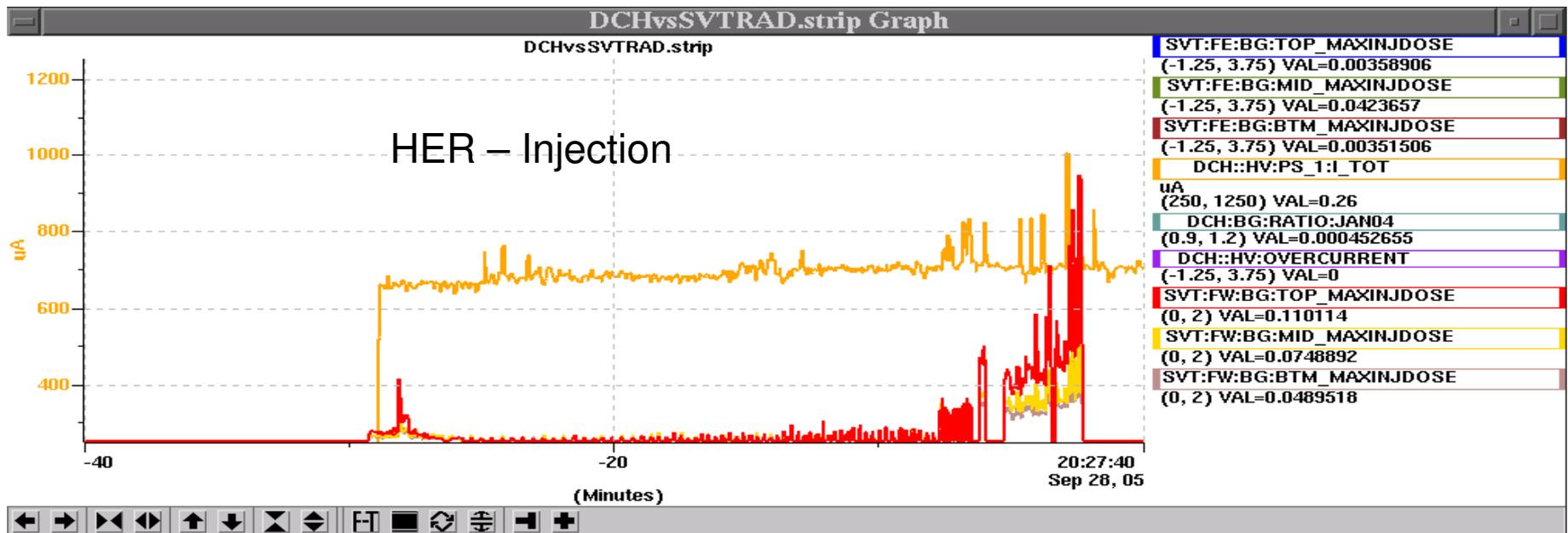
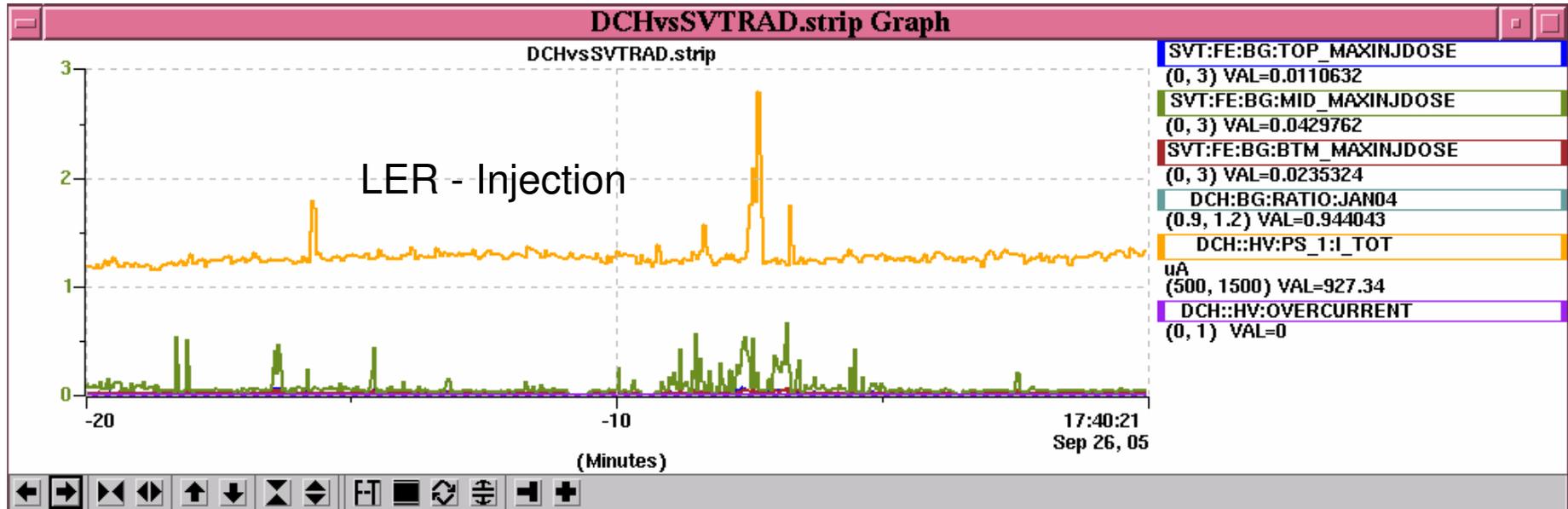


# Bad Injection - Pulse Width

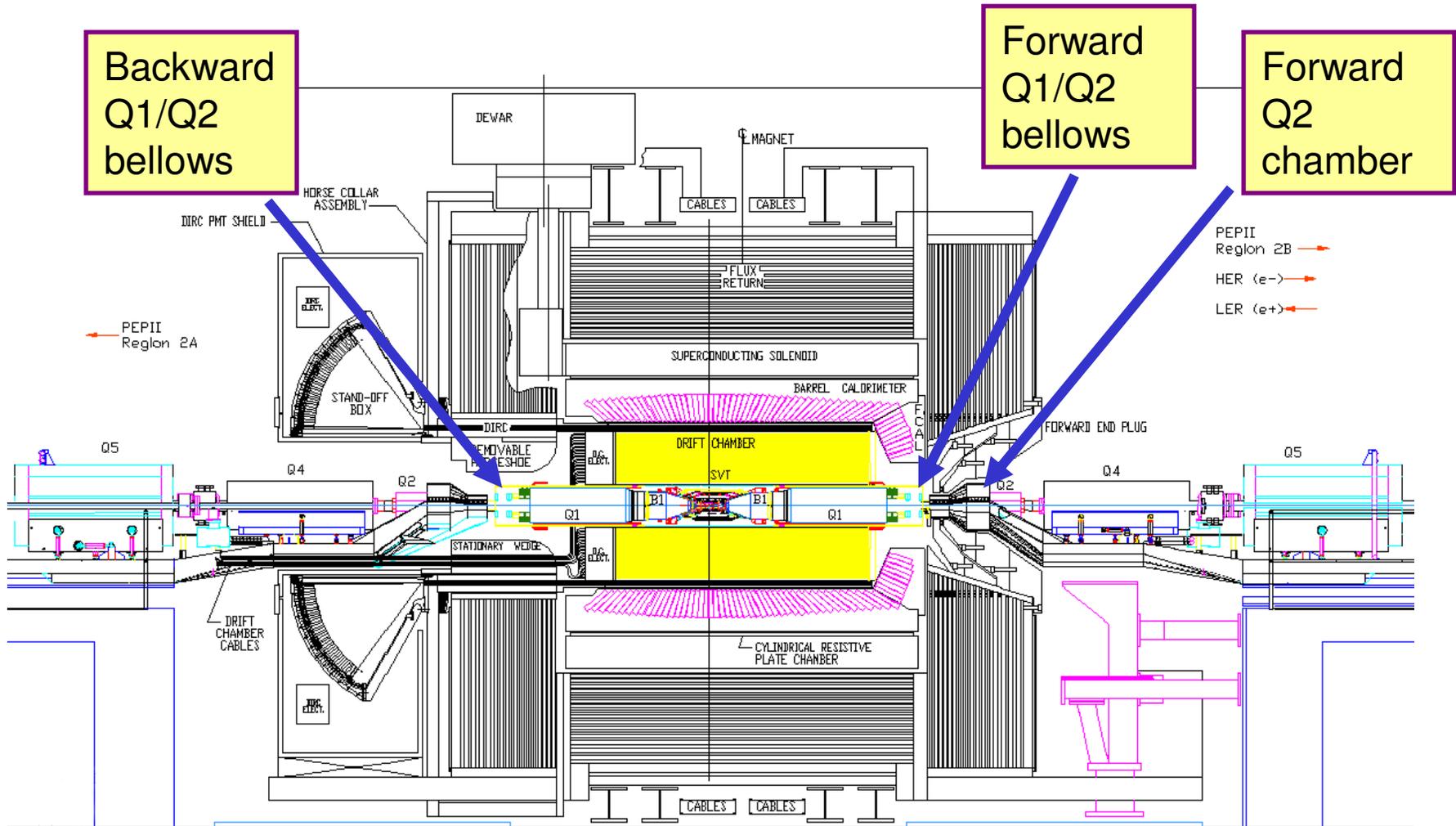
- Wide Pulses - Overlaps both Pulse and Noise + BG Windows
- Causes Large Negative Injection Dose Readings



## DCH Overcurrents and SVTRAD Max Inj Dose



# Side view of BaBar



Section through BaBar & near IR

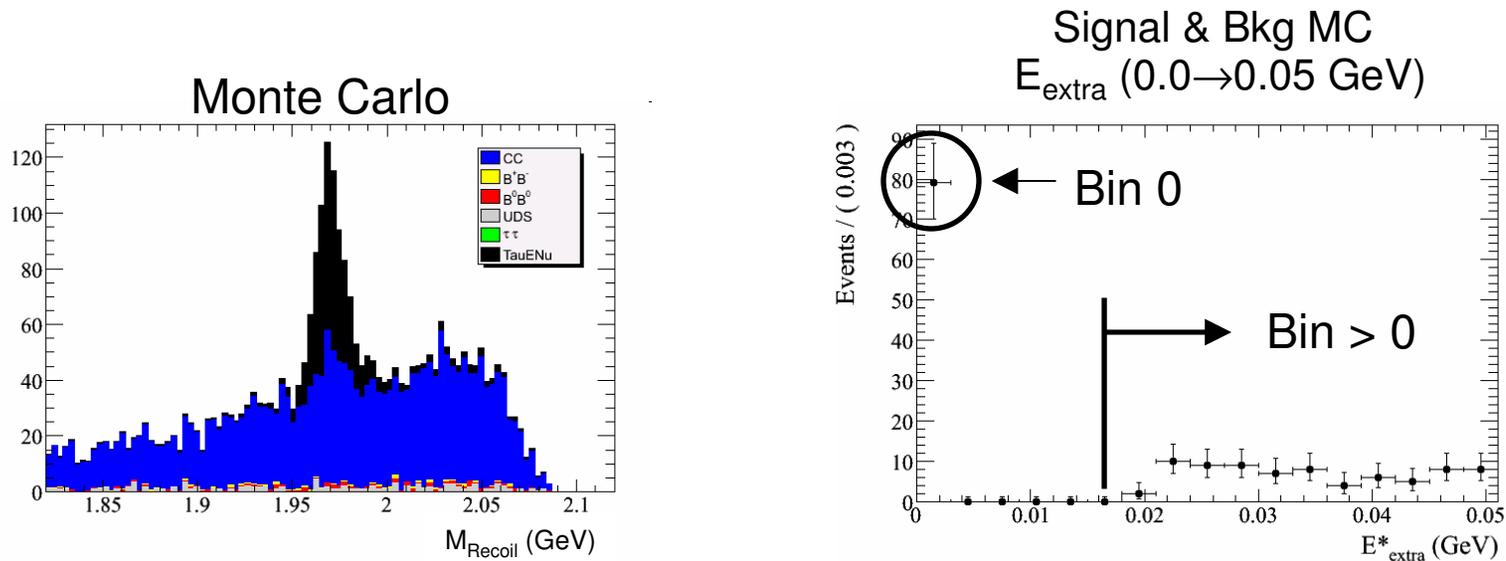
For information only, do not scale

Acad Dwg- BabarSection2  
 Dwn- S.J.Metzliffe  
 This Revision- 4/23/01

## Bellows Conclusion

- **The design flaw in the RF seal made a weak point in the system – it allowed voltage to develop between the RF seal and the Cu under the tiles**
- **When the beam currents got high enough some form of an arc damaged this tile – the tile is made of SiC 40% and AlN 60%**
- **The damaged tile could not hold off as much voltage as before and hence the maximum beam currents were limited**

# Yield Extraction - $D_s$ Mass Fit Procedure



**Separating  $E_{\text{extra}}$  Bin 0 and Bin > 0 Due to Discontinuity at Bin 0**

Use a 1-D ( $D_s$  Mass) Fit for Bin 0

Use a 2-D ( $D_s$  Mass &  $E_{\text{extra}}$ ) Fit for Bin > 0

## Fit Components

Signal

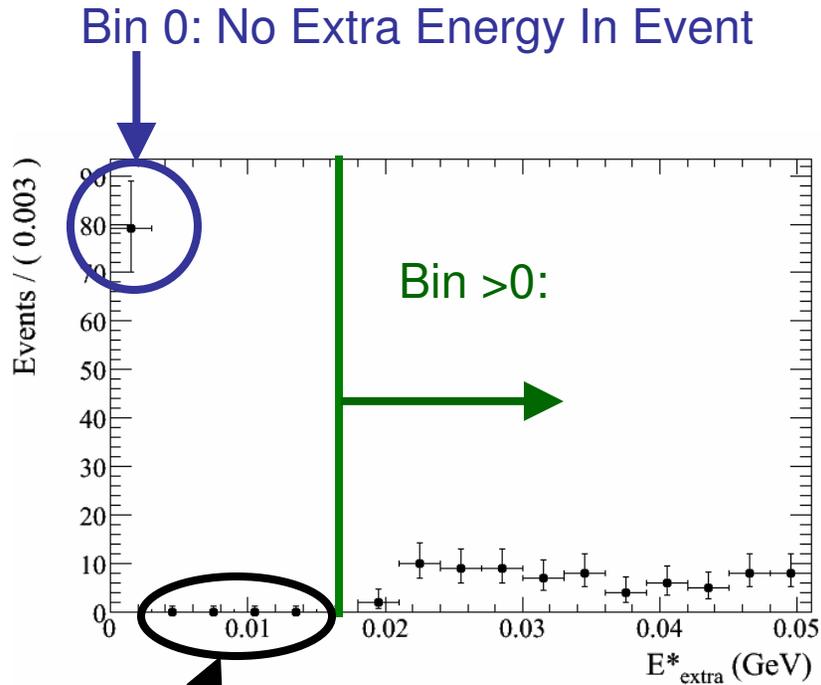
Background

Peaking Background

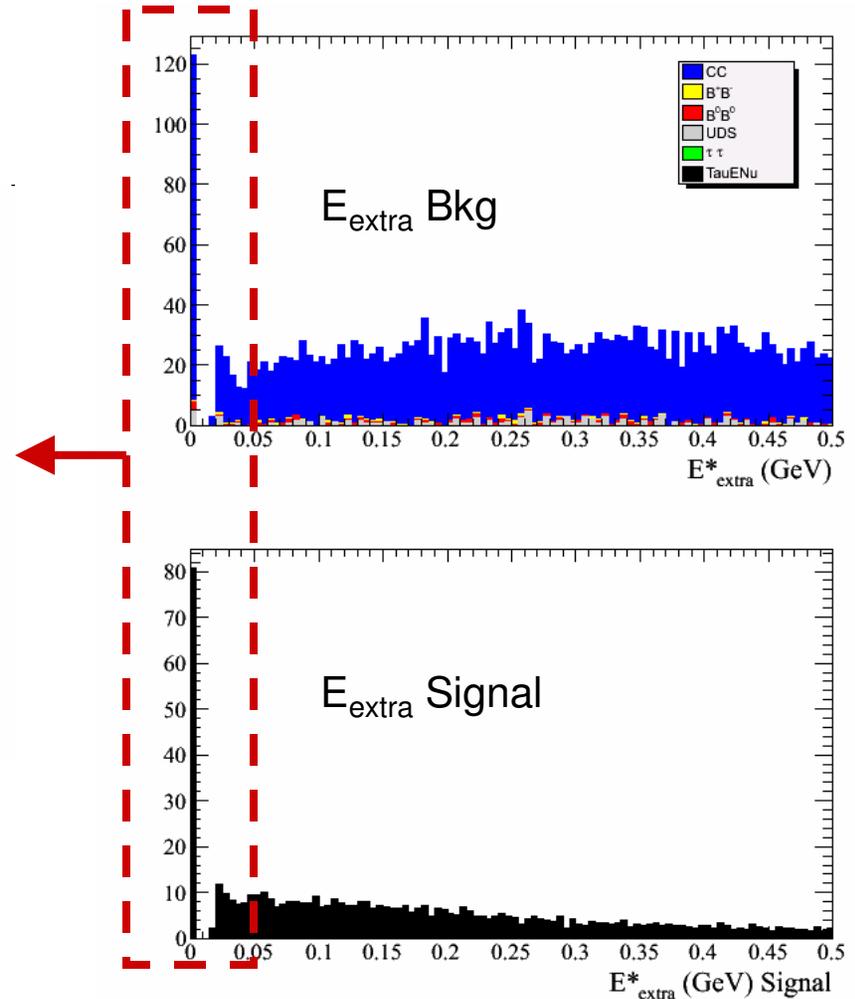
## Fit to Data:

- PDF Parameters fixed to MC
- $E_{\text{extra}}$  Bkg Shape Taken from Data Sidebands
- Float  $N_{\text{Sig}}$  and  $N_{\text{Bkg}}$ 
  - $N_{\text{PBkg}}$  Held Constant

# Closer Look at Extra Energy Monte Carlo - Normalized to 427 fb<sup>-1</sup>



The Gap in between bin 0 and the first data point above zero at 0.02 GeV is due to the minimum energy required for photon candidates.



# Systematic Errors – Cut Variables & PDF Shapes

The cut variable systematic is found by comparing the ratio of Monte Carlo and data events for  $D_s \rightarrow \tau \nu_\tau$  and  $D_s \rightarrow K_s K$ .

$$M_{N-1} \quad M_{All} \quad D_{N-1} \quad D_{All}$$

**M** = # Evts Monte Carlo

**D** = # Evts Data

**All** = All Cuts Applied

**N-1** = All Cuts Applied Except 1

$$R_{Mode} = \frac{M_{N-1}/M_{All}}{D_{N-1}/D_{All}} \quad \frac{R_e}{R_{K_s K}} \approx ?$$

$$\sigma_{CutVar} = \left| 1 - \frac{R_{D_s \rightarrow \tau \nu}}{R_{D_s \rightarrow K_s K}} \right|$$

$$\sigma_{CutVar} = 3.0\%$$

The PDFs used to extract the yields have many parameters that are found from fits to Monte Carlo. These parameters are fixed in the fit to data. The systematic error is found by varying these parameters by  $\pm 1\sigma$  and evaluating the variation of the number of fitted events. Each parameter can shift the number of events up or down, resulting in asymmetric errors.

$\tau \nu$ PDF Variables	+7.69% -4.73%
$K_s K$ PDF Variables	+4.86% -0.63%

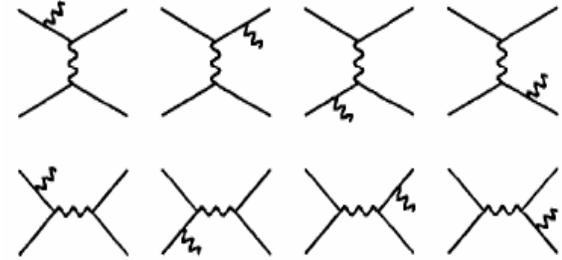
# Systematic Errors – Particle Identification

## The Electron PID Efficiency is Measured in Radiative Bhabha Events

- Very Clean

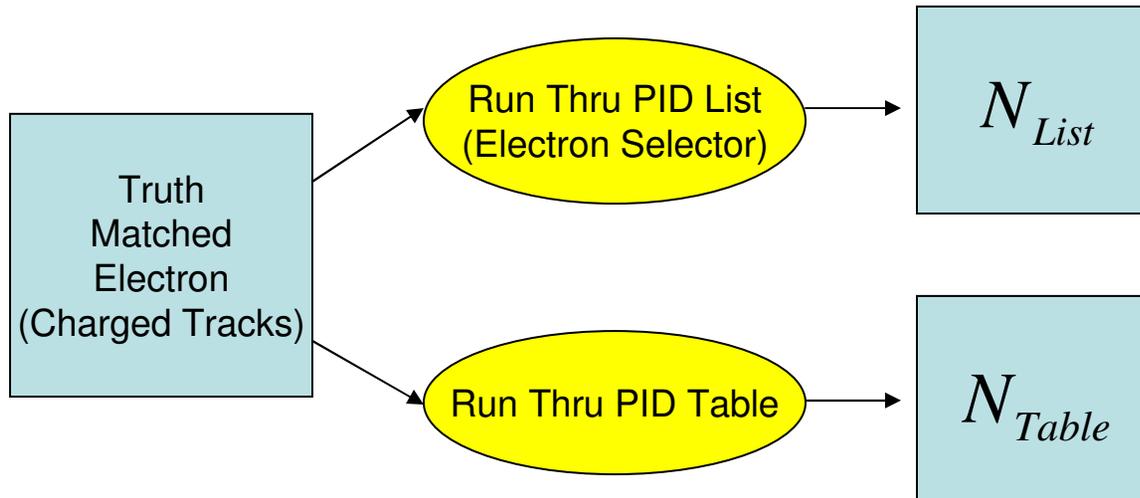
## This Analysis Contains Multihadron Events

- Results in Higher Occupancies (Calorimeter)
- Translates to Lower PID Efficiency



Bhabha Scattering

$$C = \frac{N_S^{PIDTable}}{N_S^{MC}} + \sigma_{Stat}^{PIDTable} + \sigma_{Environment}$$



PID Table - Function of Momentum and Angle

$$\sigma_{Environment} = \frac{N_{List} - N_{Table}}{N_{List}}$$

$$\sigma_{Tot} = 0.82\%$$

## Conclusion

- Measured BF and Extracted  $f_{D_s}$ 
  - $B(D_s \rightarrow \tau \nu) = (4.54 \pm 0.53 \pm 0.40 \pm 0.28) \%$
  - $f_{D_s} = (233.6 \pm 13.6 \pm 10.4 \pm 7.1) \text{ MeV}$
  - Result within  $1\sigma$  of CLEO-c & LQCD
- BAD 1994
- Journal Draft – BAD 2252
  - Intended for PRD-RC
  - Currently in RC
  - Hope to Go to CWR Soon